

# Microscopic Investigation Of Materials Limitations of Superconducting RF Cavities

aka

## RF Local Magnetometry

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**Physics Department**

**Quantum Materials Center**

**University of Maryland, USA**



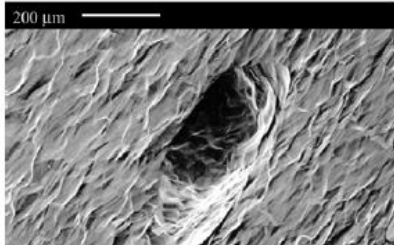
This work is funded by US Department of Energy High Energy Physics program  
grant # DESC0017931 and the Maryland Quantum Materials Center

# Outline:

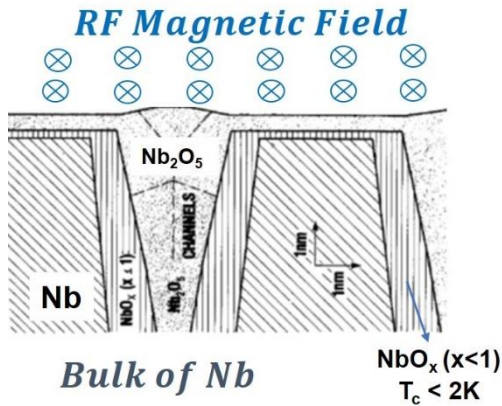
1. **What** is the issue?
2. **How** Magnetic Microwave Microscopy works?
3. **What** did we measure?
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5. **What** is the origin of this data?
6. **Where** do we plan to go with this?



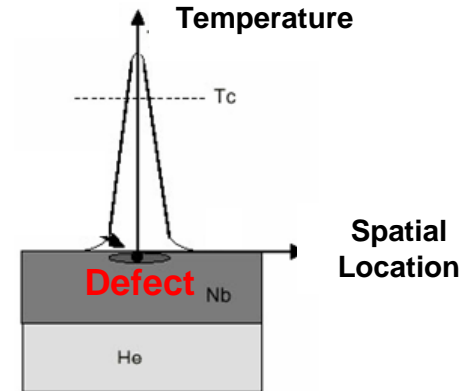
# Defects/Processes limiting SRF Performance



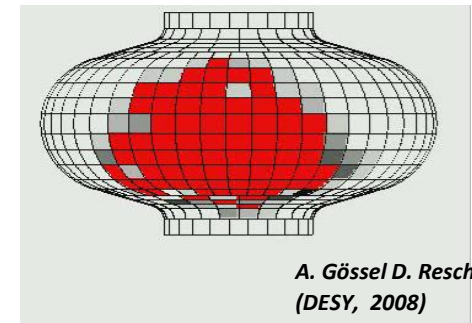
500 x 200 μm pit



1. Surface Roughness
2. Pits
3. Welds
4. Grain Boundaries
5. Nb Oxides
6. Nb Hydrides
7. Magnetic Impurities
8. Trapped Flux



Cavity Temperature Map



A. Gössel D. Reschke  
(DESY, 2008)

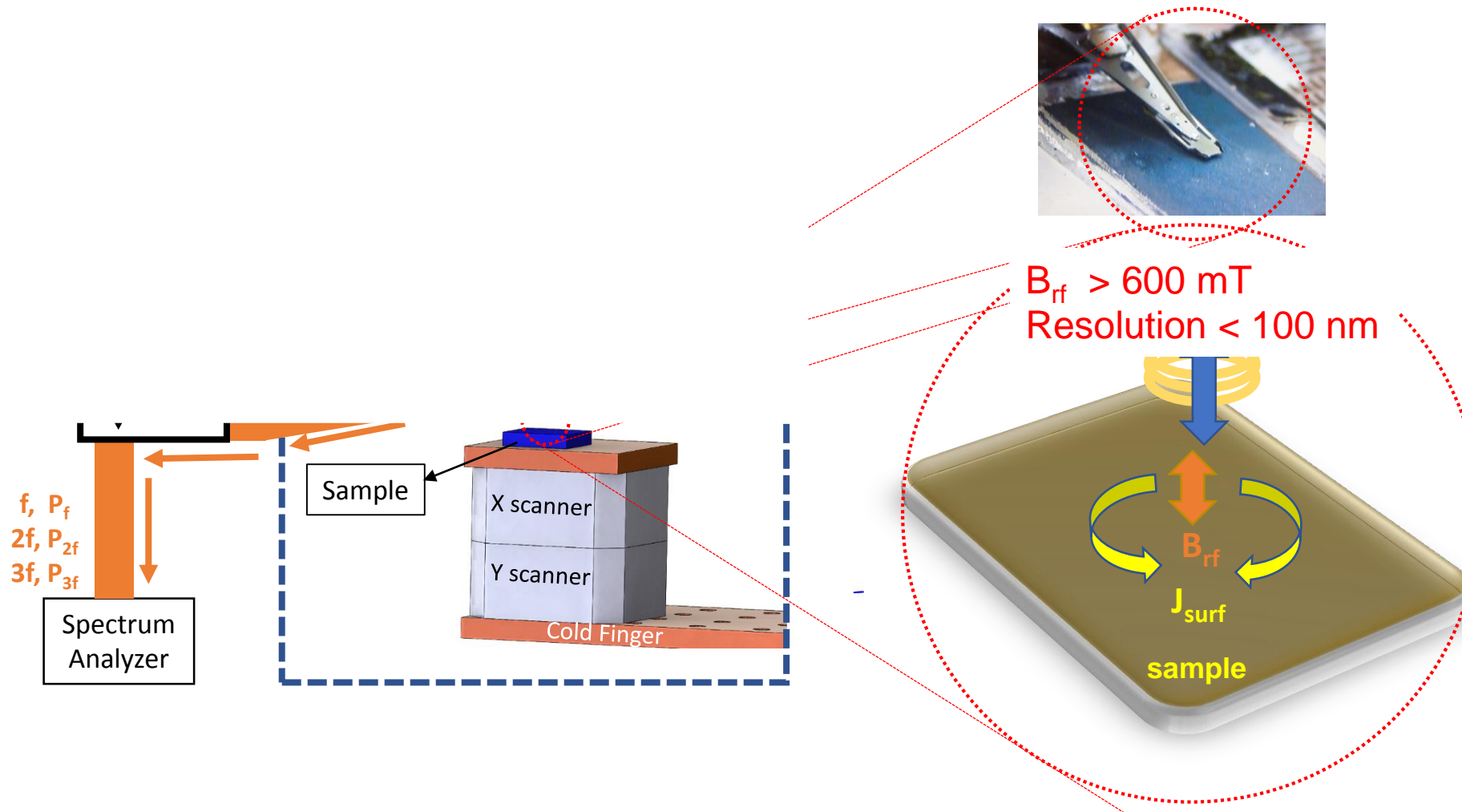
**A high resolution near-field magnetic-field microscope can identify those defects and relate which defects results in the breakdown of the cavities is needed**

# Outline:

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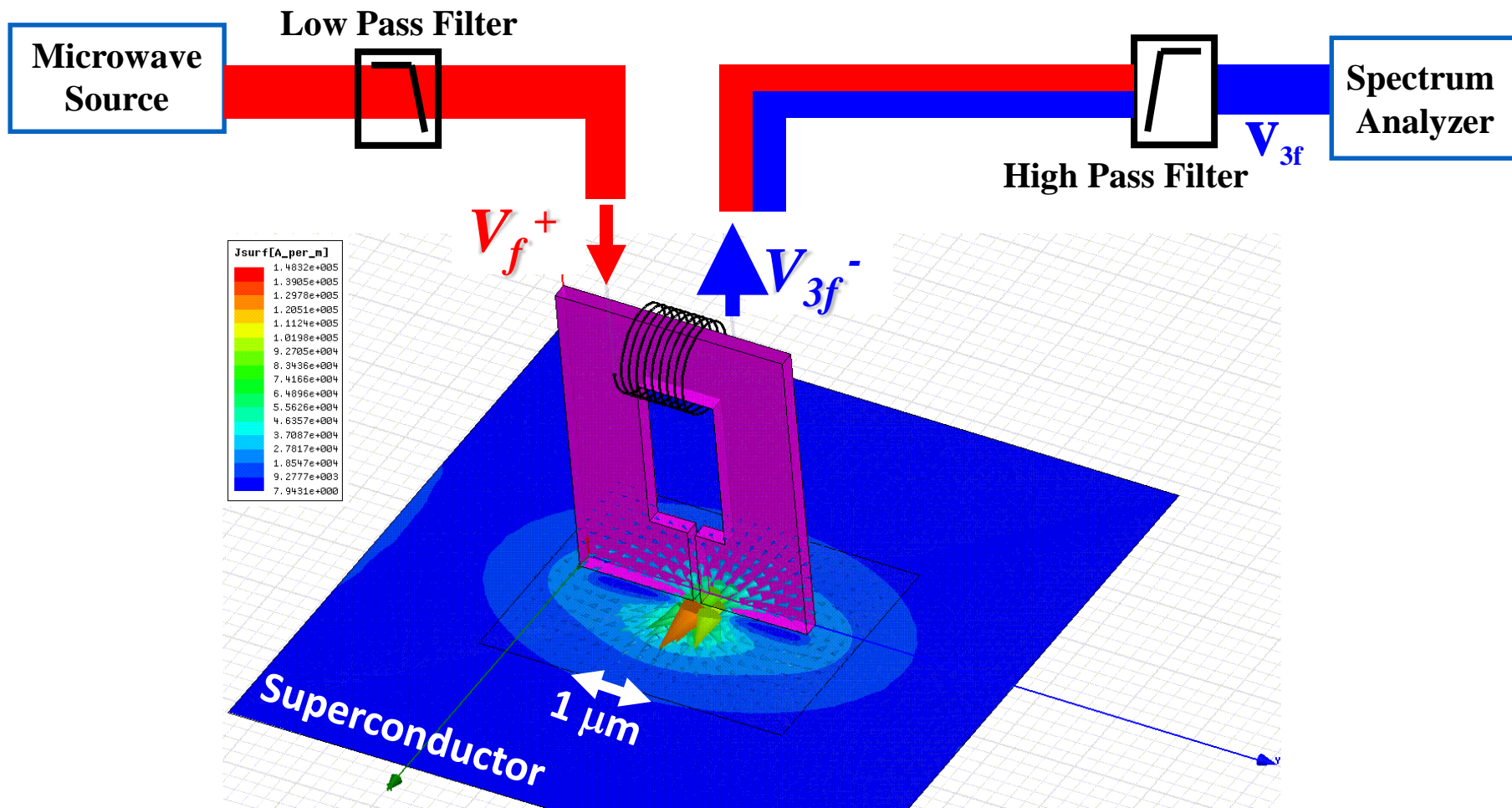
# Near-Field $B_{rf}$ Microscope



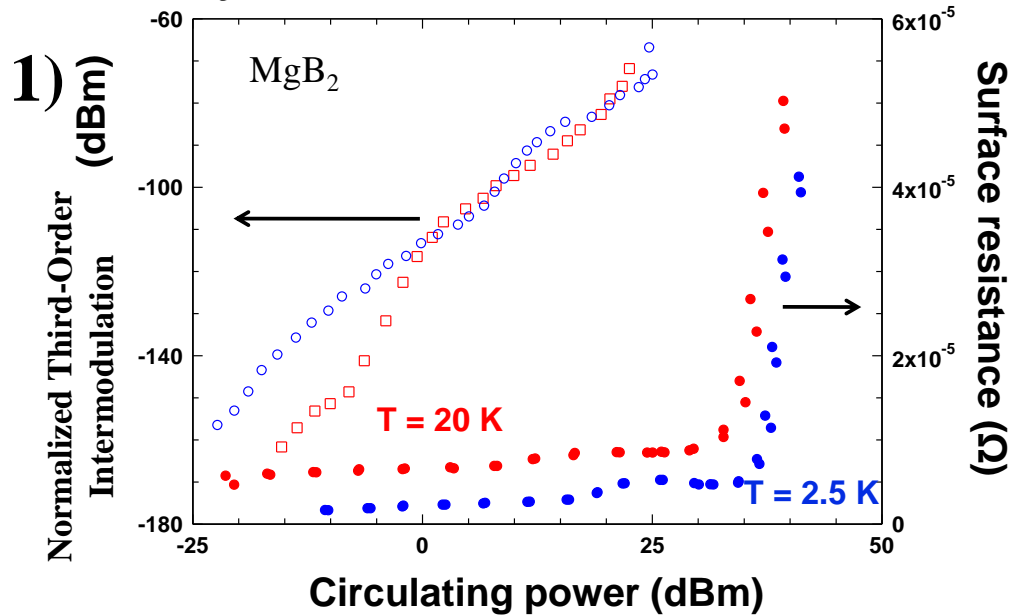
# Objective: Identify microscopic defects that cause breakdown of SRF cavities

## Method:

- 1) Examine coupons with intense, localized  $B_{RF}$  in the superconducting state
- 2) Measure locally-produced harmonic generation from defects
- 3) Scan the probe and image the response



# Why Harmonics?



D. E. Oates, Y. D. Agassi, B. H. Moeckly,  
IEEE TRANSACTIONS ON APPLIED SUPERCONDUCTIVITY, VOL. 17, NO. 2, JUNE 2007

comparison to  
SRF conditions

	SRF Cavity	Magnetic Probe Microscopy
Temperature	2 K	3.6 K - $T_c$
RF Magnetic Field	$\approx 200\text{ mT}$	$\approx 200\text{ mT}$
Frequency	1.3 GHz	1.0 – 6.0 GHz

2) Each defect type will have different nonlinear signature

3) Superconductor is the main source of Nonlinearity

- RF Characterization
  - Localized / No Edge Effect
- Can Measure Flat Samples of any shape

# Outline:

1. **What** is the issue?
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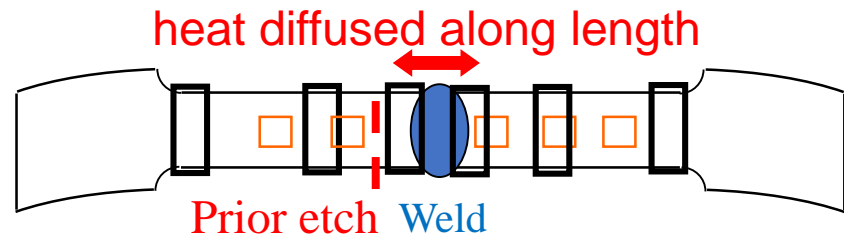


# Bulk Nb Sample

**Deformed ( $\epsilon \sim 0.4$ )  
single crystals  
pulled apart,  
Etched for 10 min  
then welded back  
together**

Sample prepared by Tom Bieler's group

**MICHIGAN STATE  
UNIVERSITY**



# Microwave Microscope Probe and Sample (Fixed Position Measurement)

Thermometer

4K Plate

Coaxial  
Cable

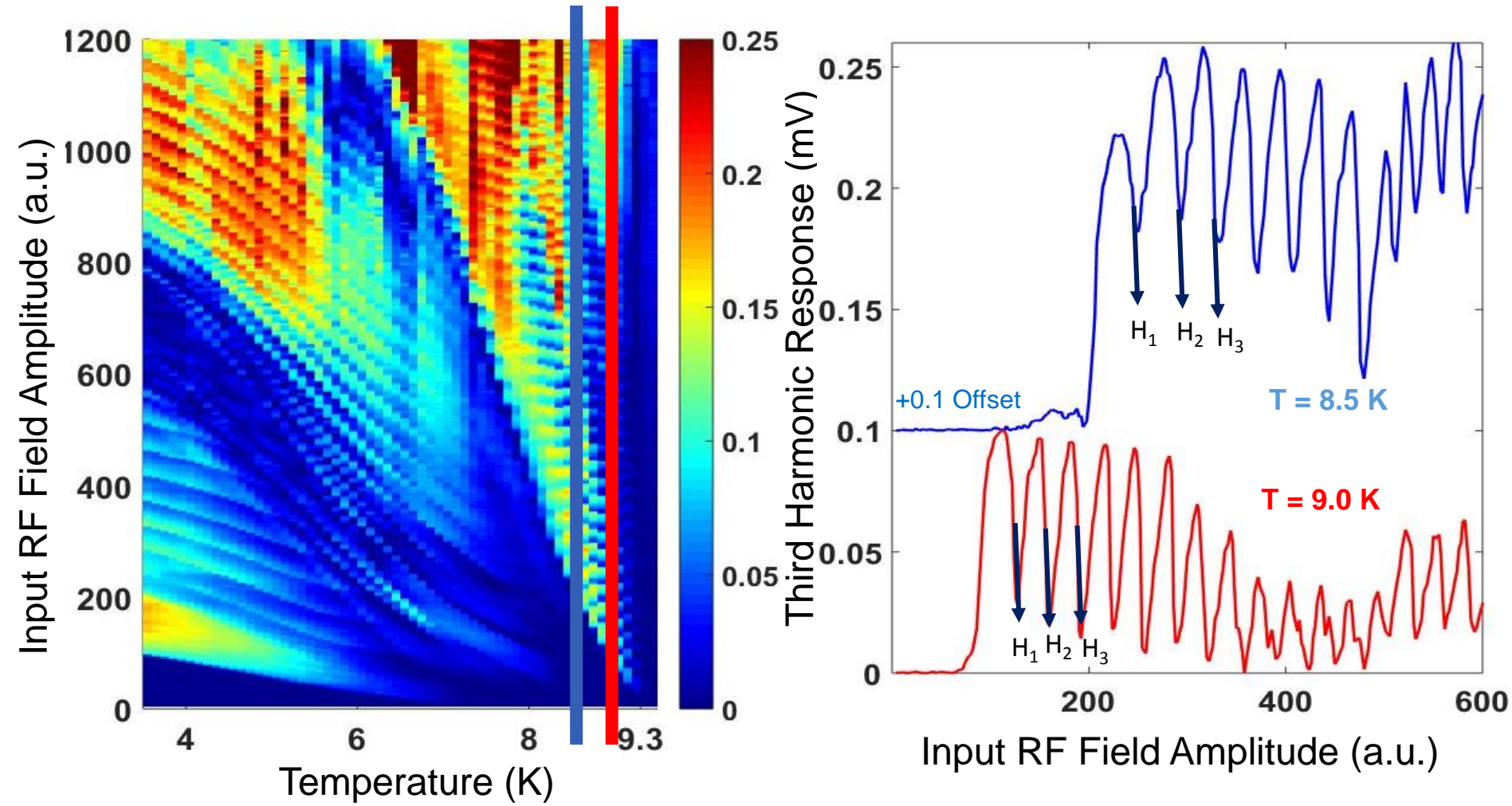
Sample

Transmission  
Line

Probe

Connection  
to Probe

# Bulk Nb Data: Periodicity in Harmonic Response



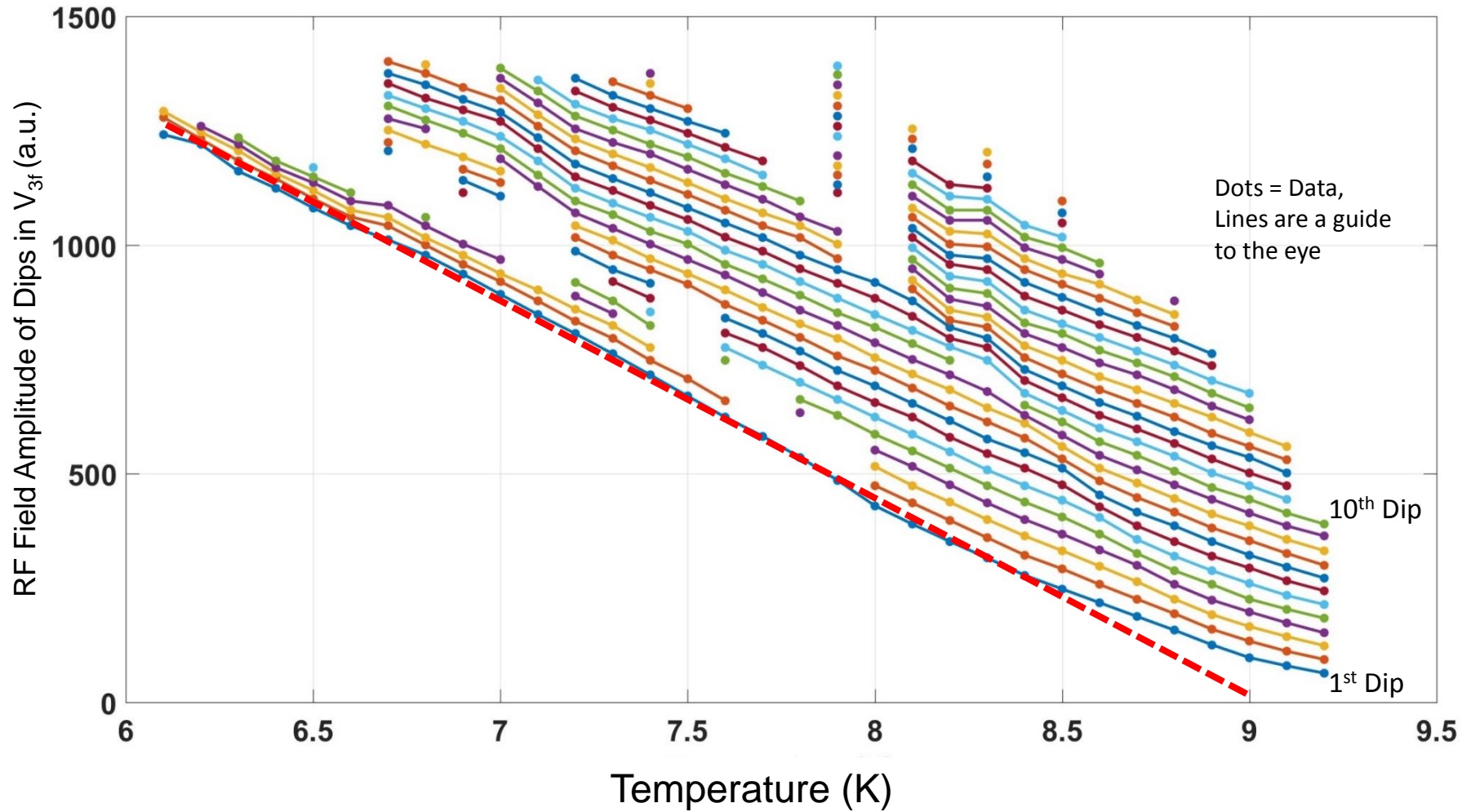
$f = 4.38 \text{ GHz}$

Probe background nonlinearity subtracted

RF Amplitude scale estimate:

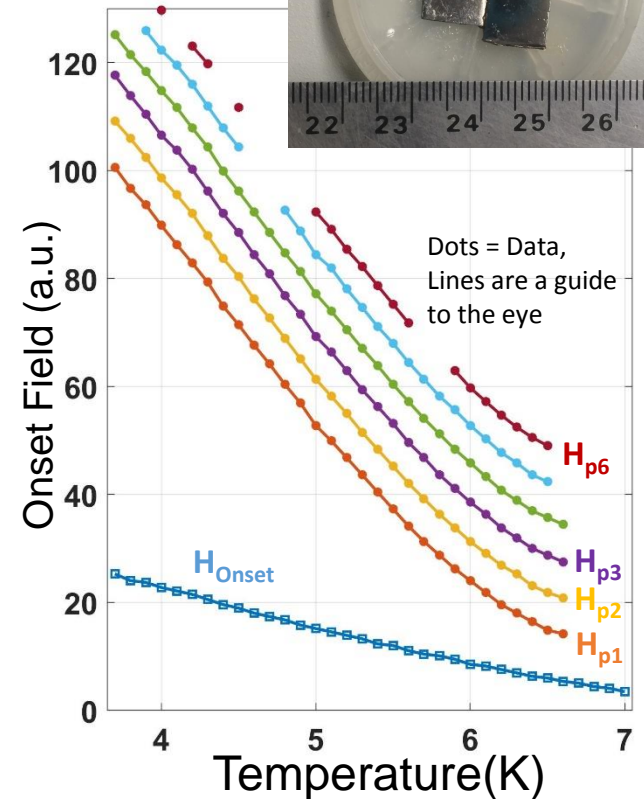
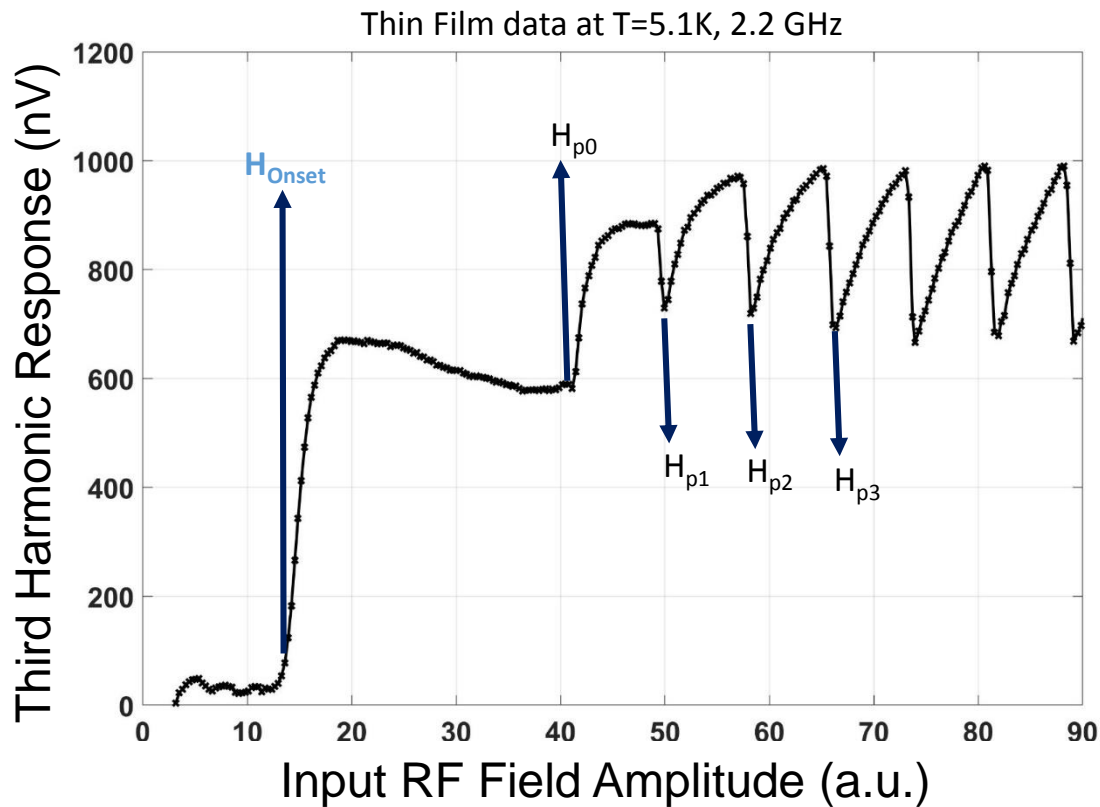
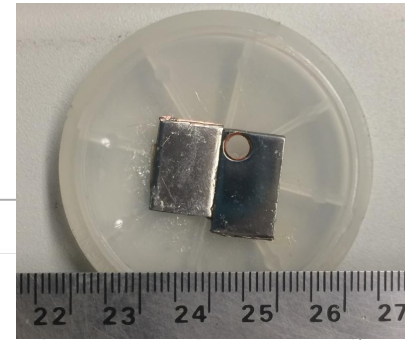
$11.4 \mu\text{T}/(\text{arb. units})$  for weak link #1

# Bulk Nb Data: Closer look at Dips



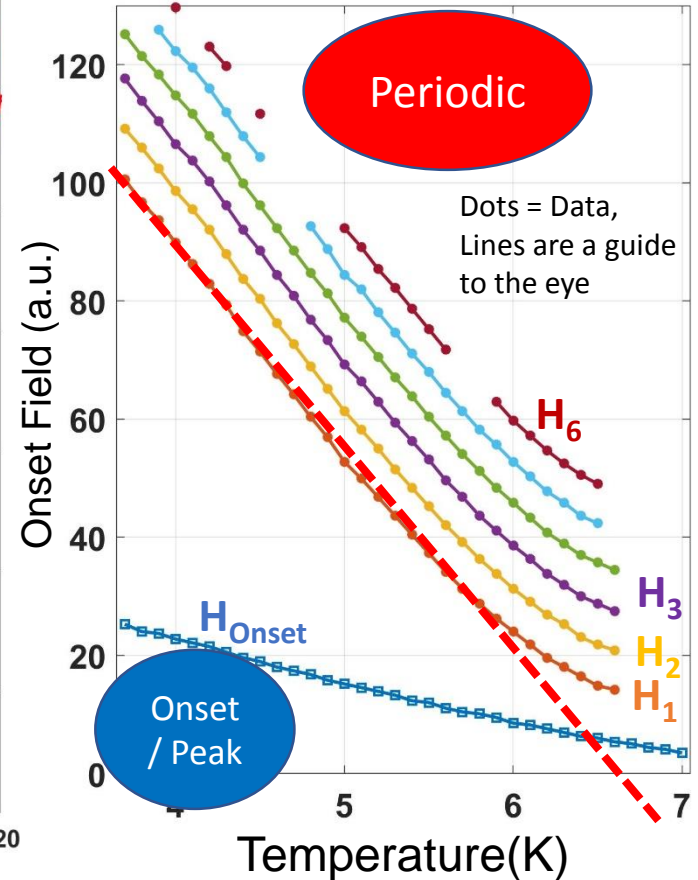
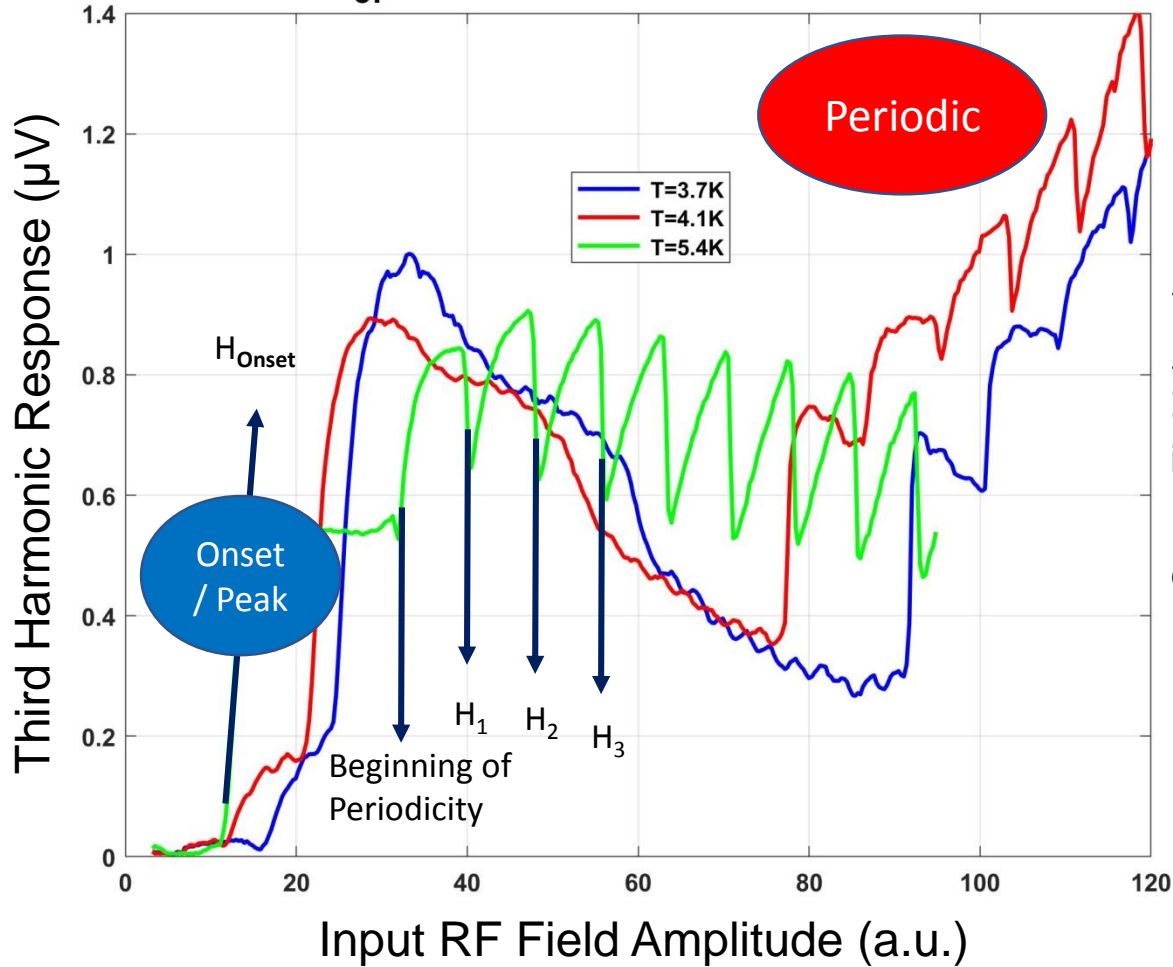
# Nb Film on Copper samples from CERN

- Deposited by high-power impulse magnetron sputtering (HIPIMS)
- Highly Granular (grain size around 10 nm)
- 1  $\mu\text{m}$  Nb / Cu



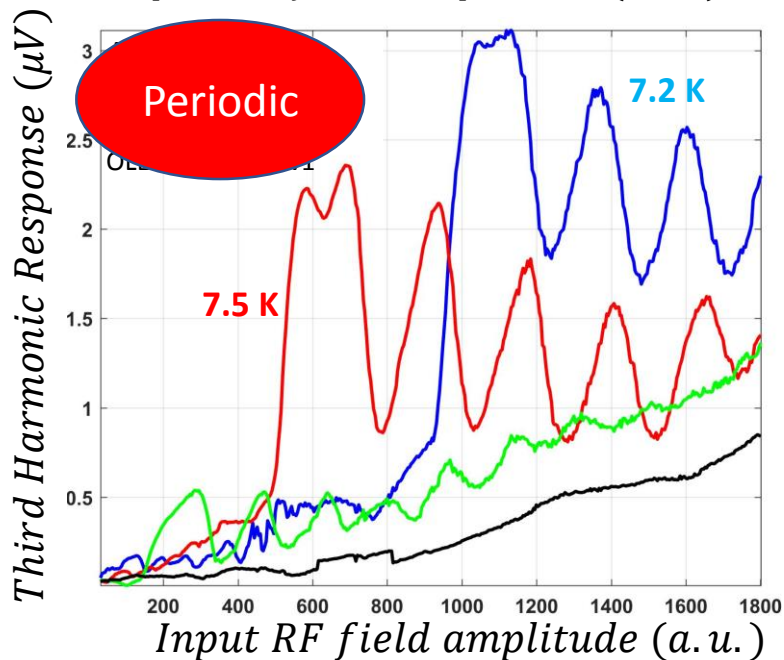
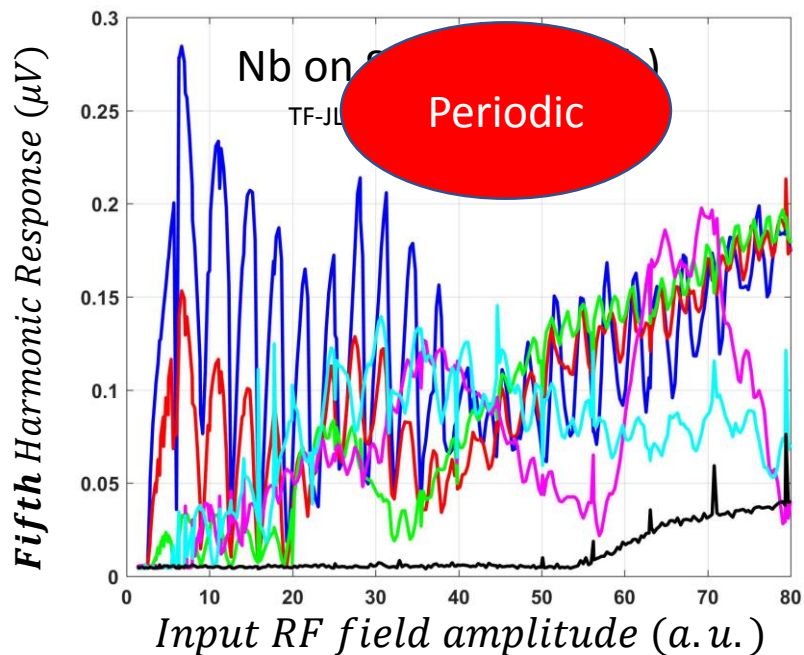
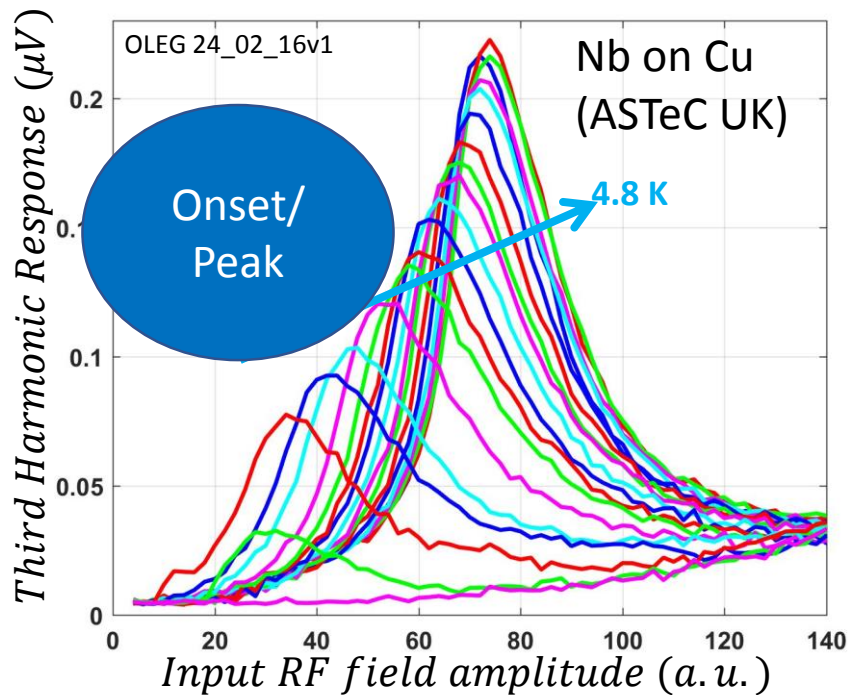
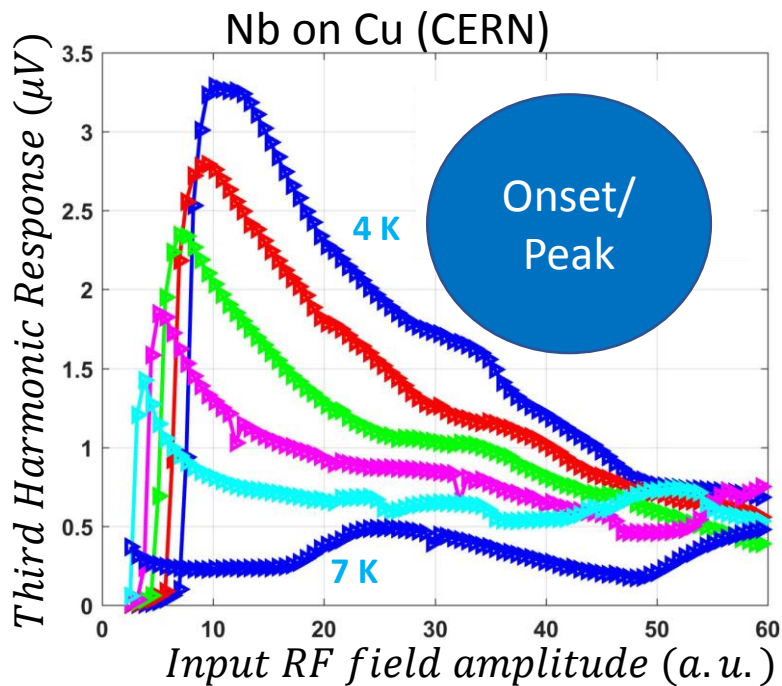
# Nb on Copper samples from CERN

$V_{3f}$  vs Applied Field (Combined)

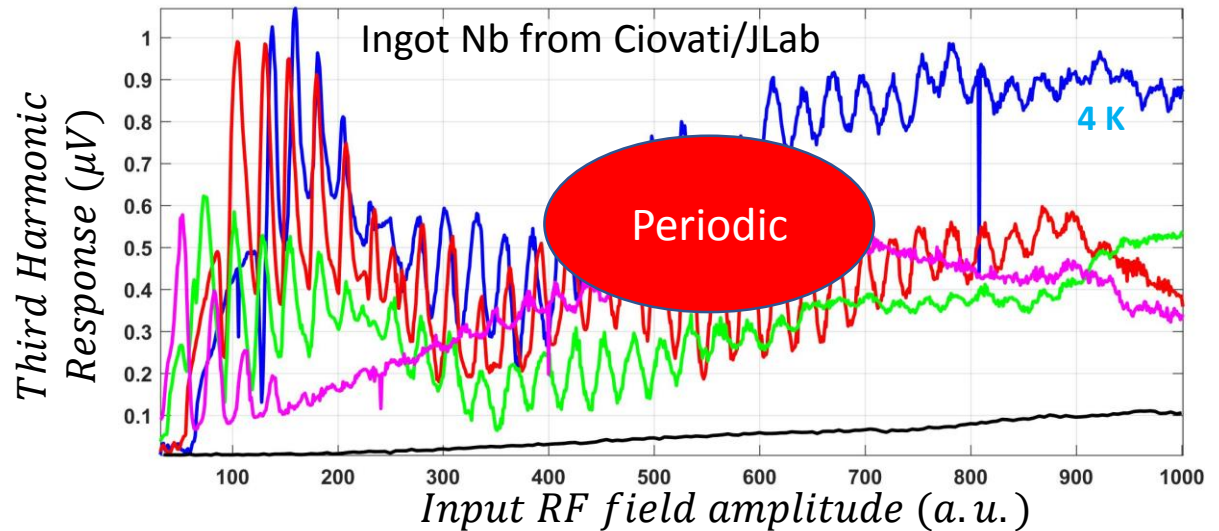
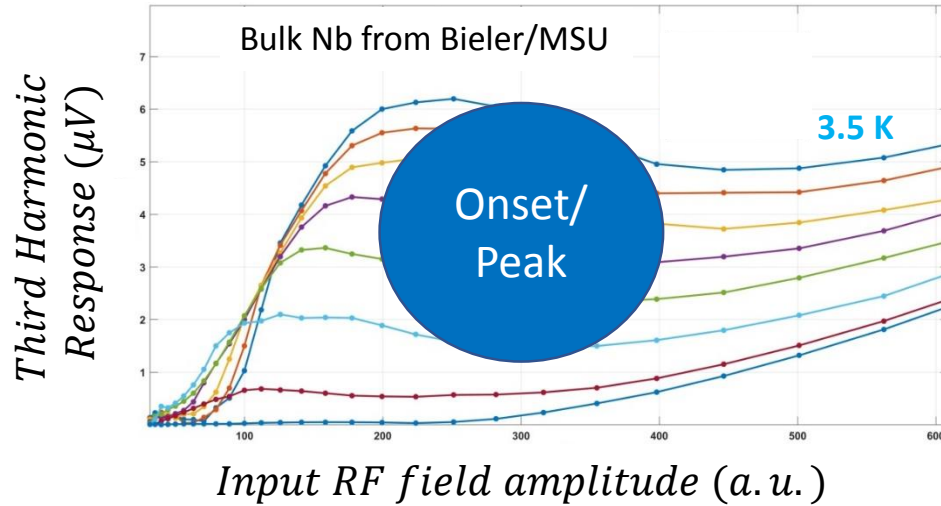


$f = 2.2 \text{ GHz}$

# Similar Results Seen on Other Film Samples



# Similar Results Seen on Bulk Samples



**Bulk and Film samples can show either periodic or non-periodic harmonic response depending on location**

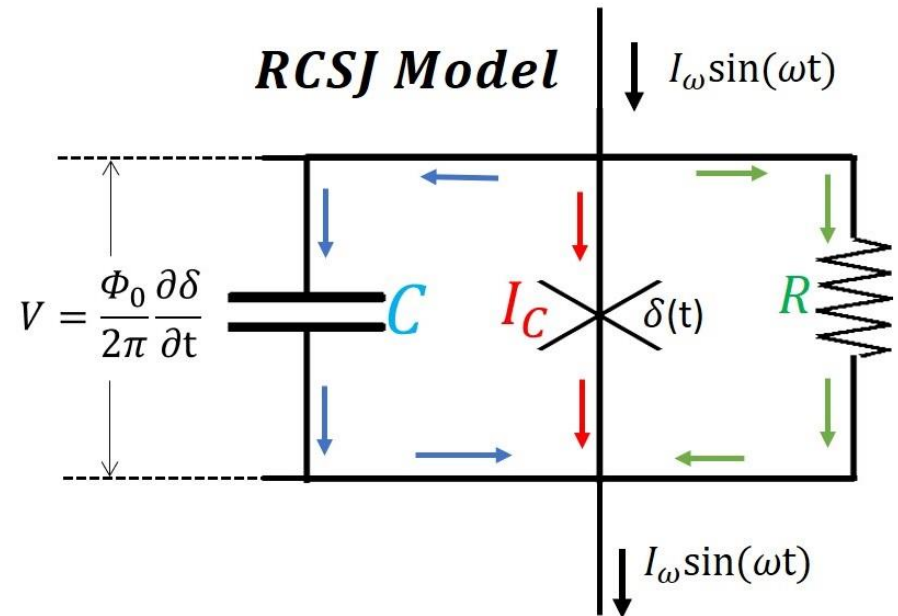
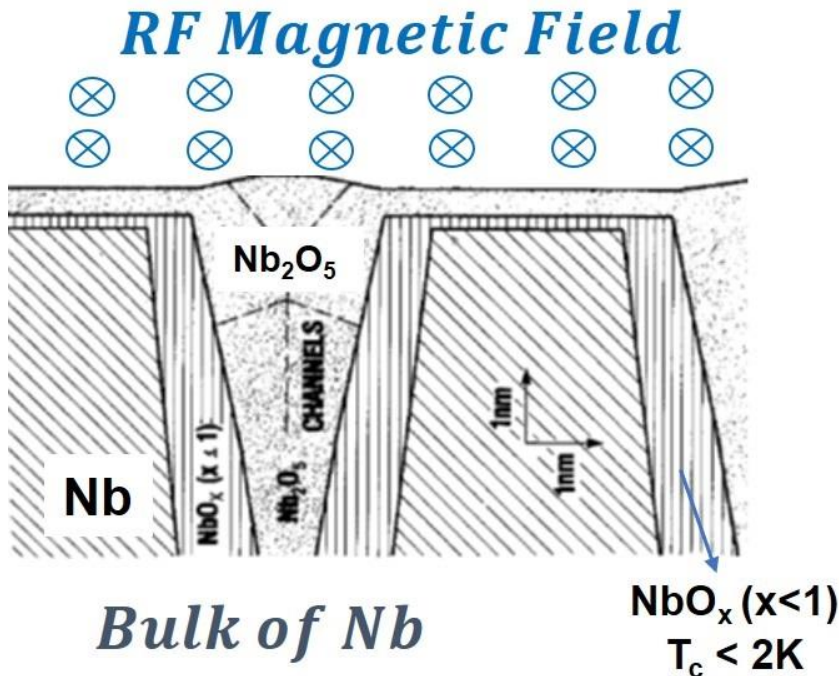


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# Current Driven Resistively and Capacitively Shunted Josephson Junctions (RCSJ) model



$$\frac{\Phi_0 C}{2\pi} \frac{\partial^2 \delta}{\partial t^2} + I_C \sin \delta + \frac{\Phi_0}{2\pi R_n} \frac{\partial \delta}{\partial t} = I_\omega \sin(\omega t)$$

J. Halbritter, "On the Oxidation and on the Superconductivity of Niobium," J. Appl. Phys. A 43, 1 (1987).

L. M. Xie, J. Wosik, and J. C. Wolfe, "Nonlinear microwave absorption in weak-link Josephson junctions," Phys. Rev. B 54, 15494 (1996).

J. McDonald and John R. Clem, "Microwave response and surface impedance of weak links," Phys. Rev. B 56, 14723 (1997).

# Example Solution to the RCSJ Model and Fit

## Solution to the RCSJ Model

$$\frac{\Phi_0 C}{2\pi} \frac{\partial^2 \delta}{\partial t^2} + I_C \sin \delta + \frac{\Phi_0}{2\pi R_n} \frac{\partial \delta}{\partial t} = I_\omega \sin(\omega t)$$

Short Junction Approximation

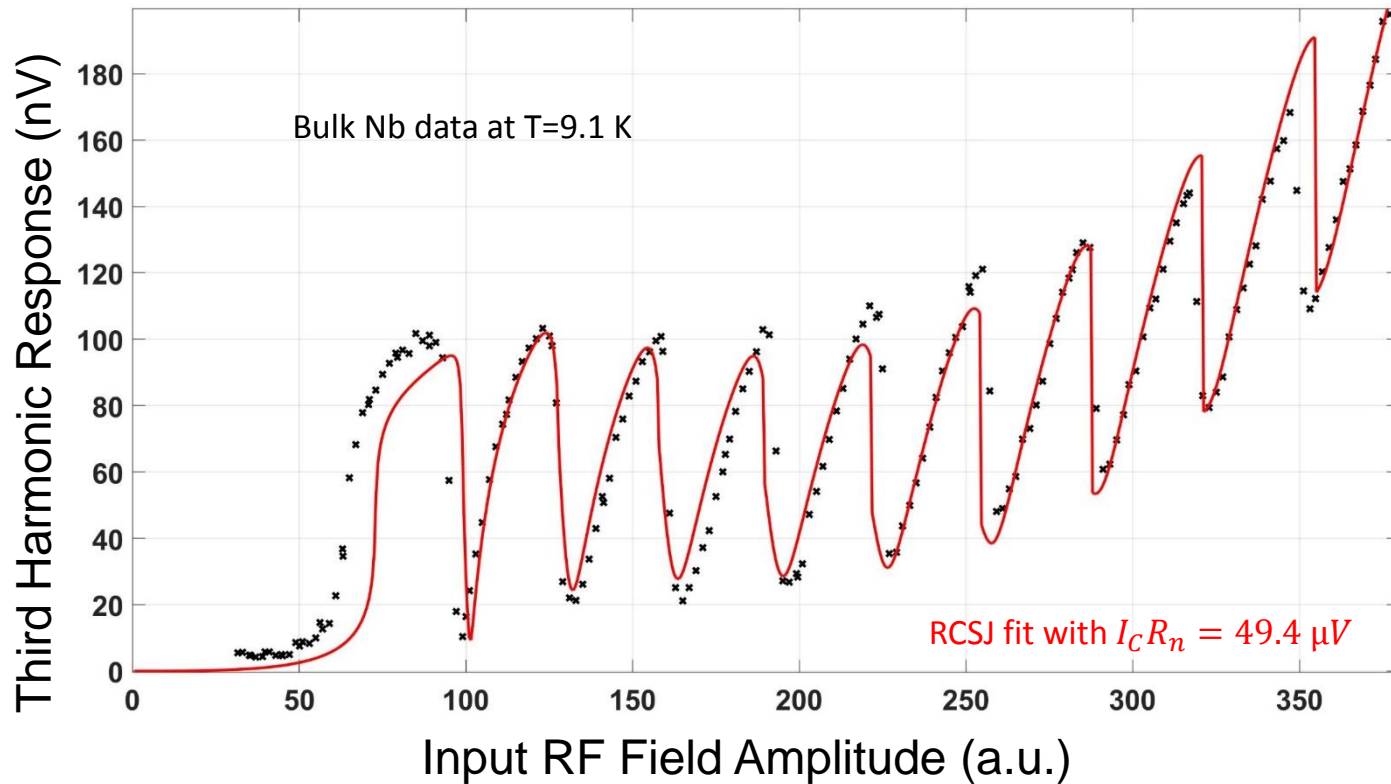
All Dimensions Perpendicular to the field  $\ll \lambda_J$

$$(I_C R_n) \sin \delta + \frac{\Phi_0}{2\pi} \frac{\partial \delta}{\partial t} = (I_\omega R_n) \sin(\omega t)$$

$I_C R_n$  - Fitting Parameter

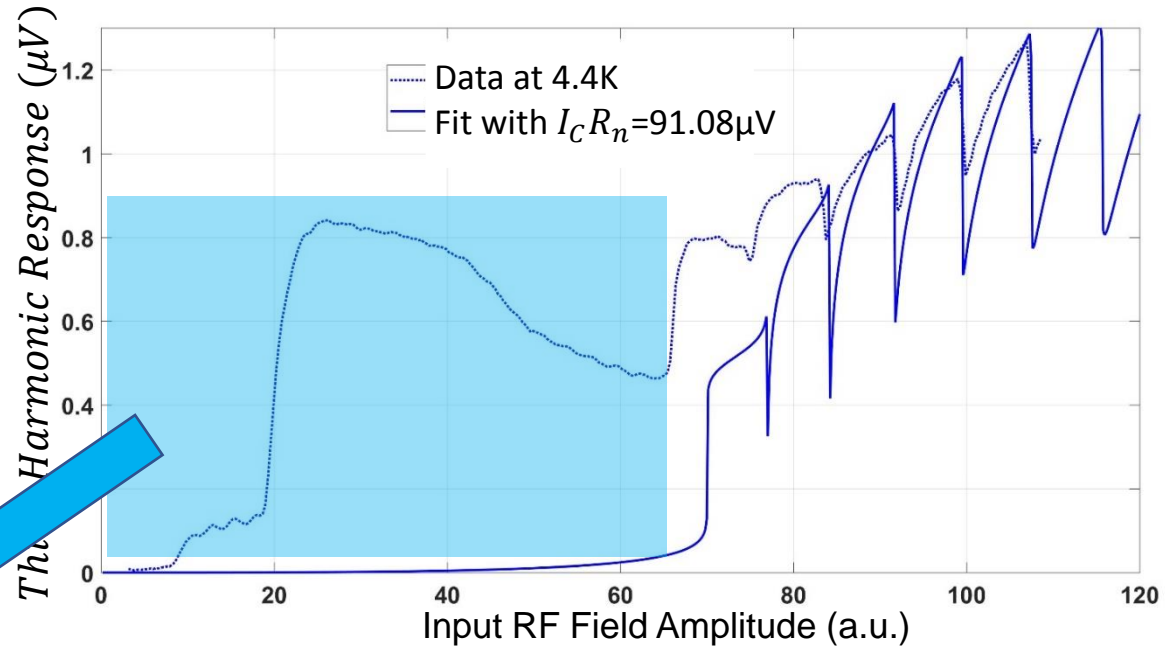
$I_\omega R_n$  - ScalingFactor \* Input RF Field Amplitude (a.u.)

$$\delta(t) \rightarrow V(t) \rightarrow V_{3\omega}$$

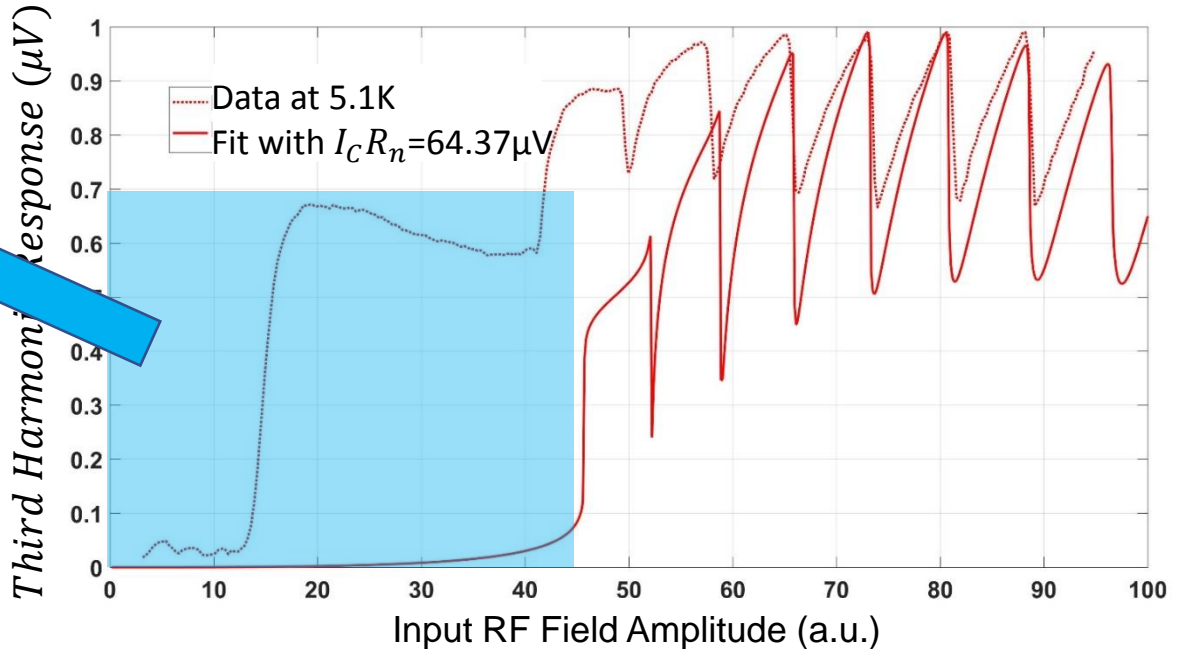


# Additional (Non-Periodic) Feature in the Data

**Nb on Cu Data  
measured at  $f = 2.2$  GHz**



Nonperiodic low input  
RF field data is not  
fitted and has a  
different origin.



# Other Sources of Nonlinear Response

## RF Vortex Entry and Motion in the Superconductor

PHYSICAL REVIEW B 77, 104501 (2008)

Dynamics of vortex penetration, jumpwise instabilities, and nonlinear surface resistance of type-II superconductors in strong rf fields

A. Gurevich<sup>1</sup> and G. Ciovati<sup>2</sup>

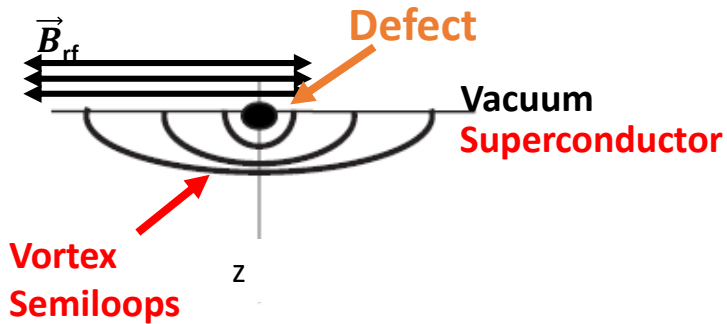
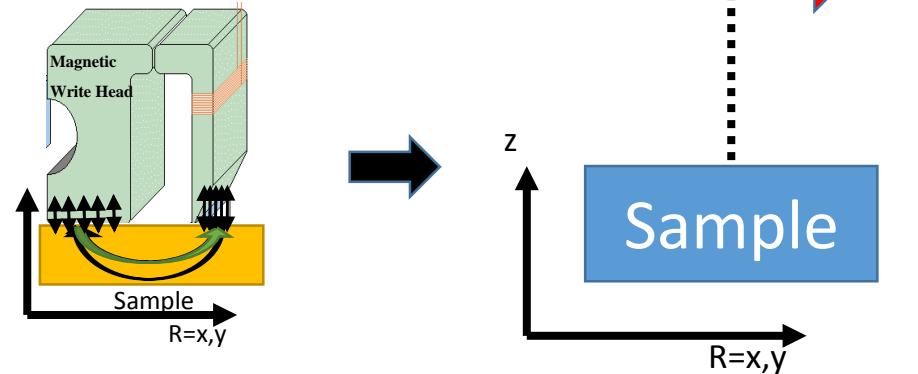


FIG. 2. Snapshots of an expanding vortex semiloop emerging from a surface defect (black dot). The quicker expansion of the loop

TDGL Equations:

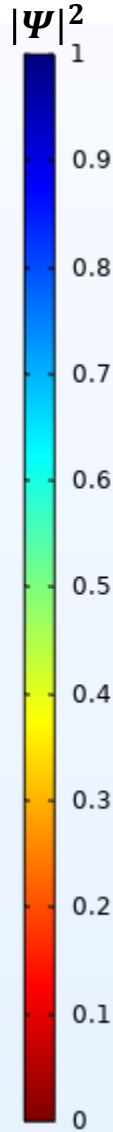
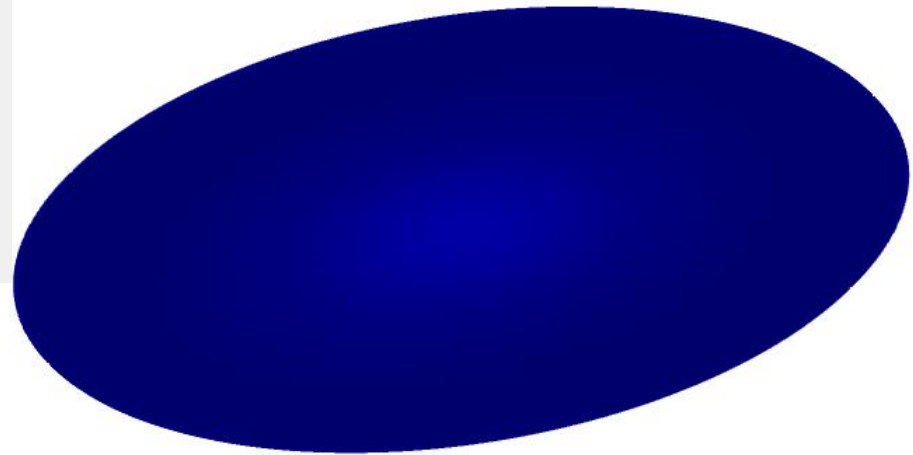
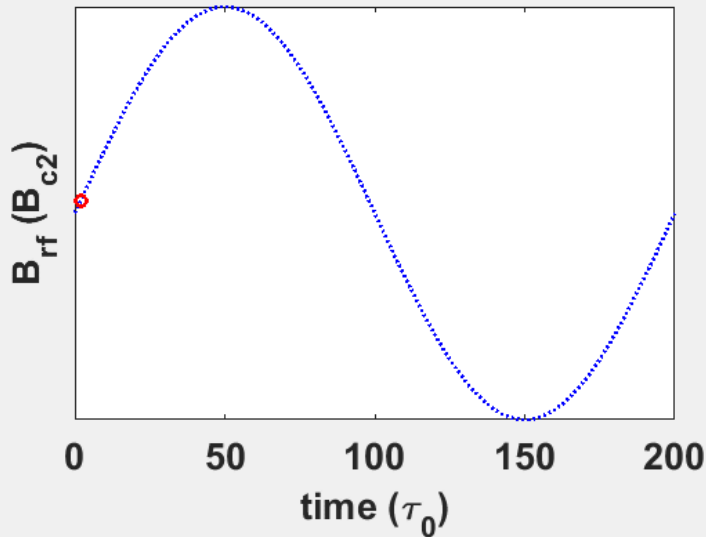
$$\eta \frac{\partial \Psi}{\partial t} = - \left( \frac{i}{\kappa} \vec{\nabla} + \kappa \vec{A} \right)^2 \Psi + (1 - T - |\Psi|^2) \Psi$$

$$\vec{\nabla} \times \vec{\nabla} \times \vec{A} = \underbrace{-\sigma \frac{\partial \vec{A}}{\partial t}}_{J_n} - \underbrace{\frac{i}{2\kappa^2} (\Psi^* \vec{\nabla} \Psi - \Psi \vec{\nabla} \Psi^*)}_{J_s} - |\Psi|^2 \vec{A}$$



B. Oripov, SMA, arXiv:1909.02714

# Horizontal RF Dipole Above Superconductor

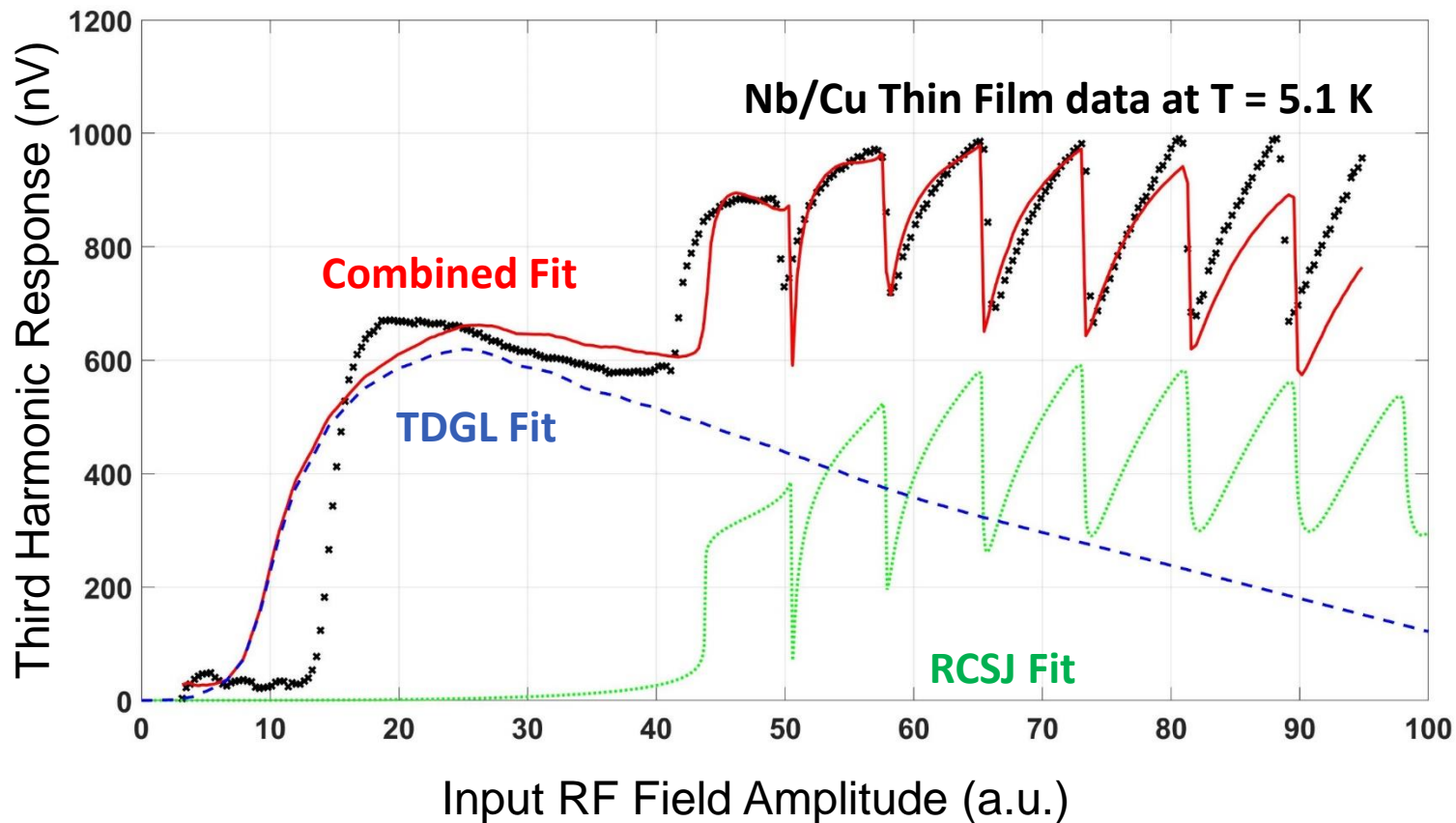


$H_{\text{dipole}} = 8 \lambda$     $\kappa = 1$   
 $B_{\text{dipole}} = 0.75 B_{c2}$     $\eta = 1$   
Period =  $200 \tau_0$     $T = 0$   
Frequency  $\approx 5$  GHz   **NO DEFECTS**

**NO DC Magnetic Field**

Silver (3D) surface corresponds to  $|\Psi|^2 = 0.005$

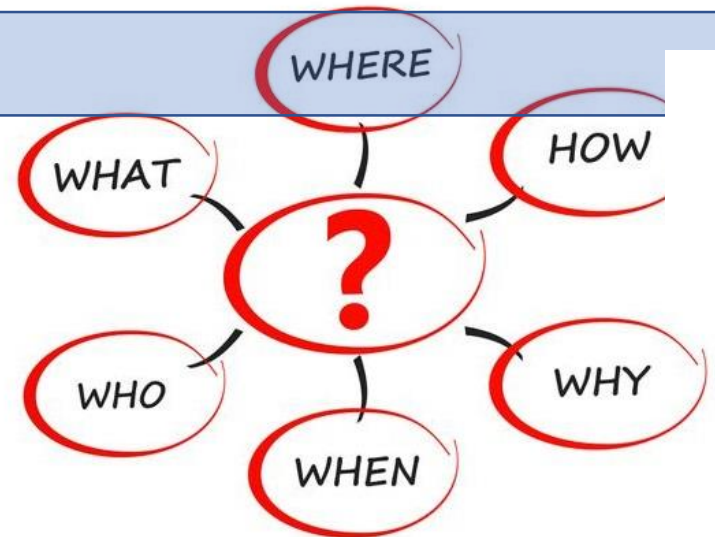
## Comparing TDGL with Data



B. Oripov, *et al.*, Phys. Rev. Applied **11**, 064030 (2019)

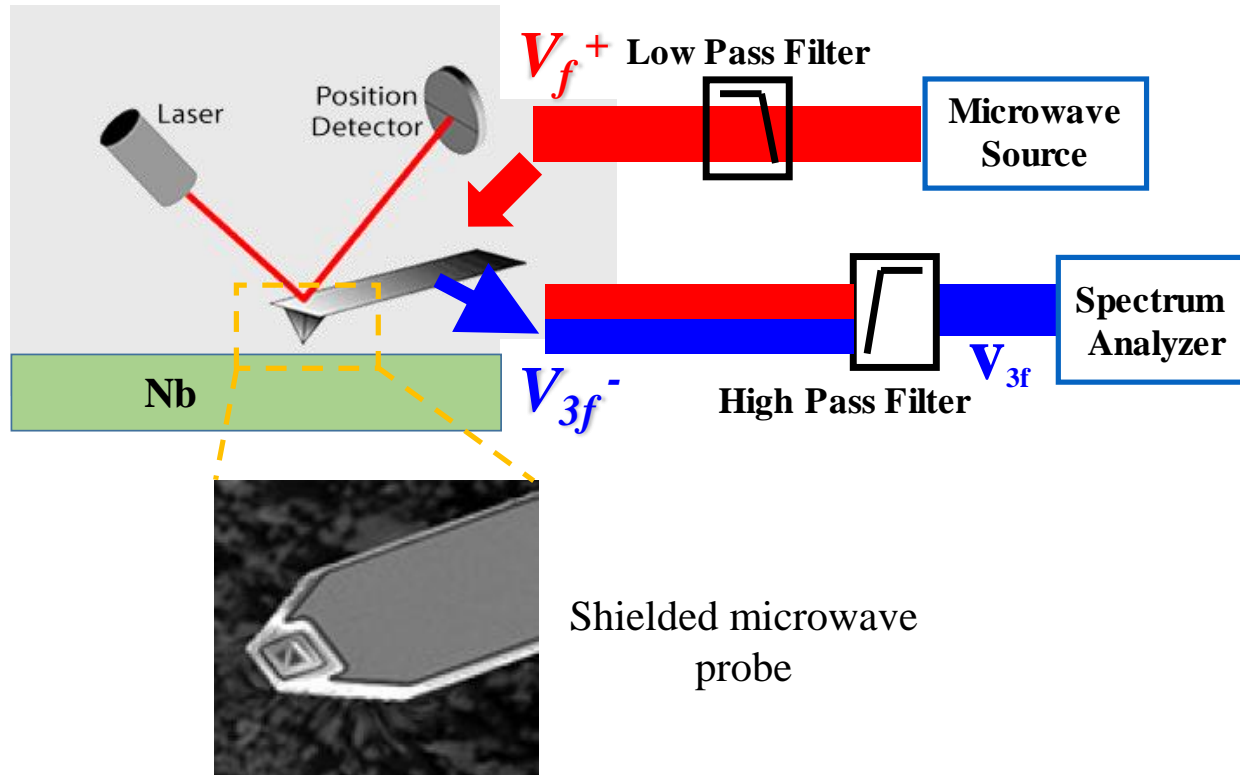
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# Atomic Force Microscopy (AFM) Based Microwave Microscope



**Scanned Nonlinear response imaging**

**Correlate  $P_{3f}(x, y)$  images with topography, surface potential, etc.**

# Thermal Properties of Nb Coatings and Interfaces

Supercond. Sci. Technol. 29 (2016) 015004 (12pp)

doi:10.1088/0953-2048/29/1/015004

## Thermal contact resistance at the Nb/Cu interface as a limiting factor for sputtered thin film RF superconducting cavities

V Palmieri<sup>1</sup> and R Vaglio<sup>2</sup>

### Proposal:

Measure thermo-reflectance of Nb/Cu coatings to deduce the thermal boundary resistance  $R_{Nb/Cu}$

### Expected outcome:

#### Determination of:

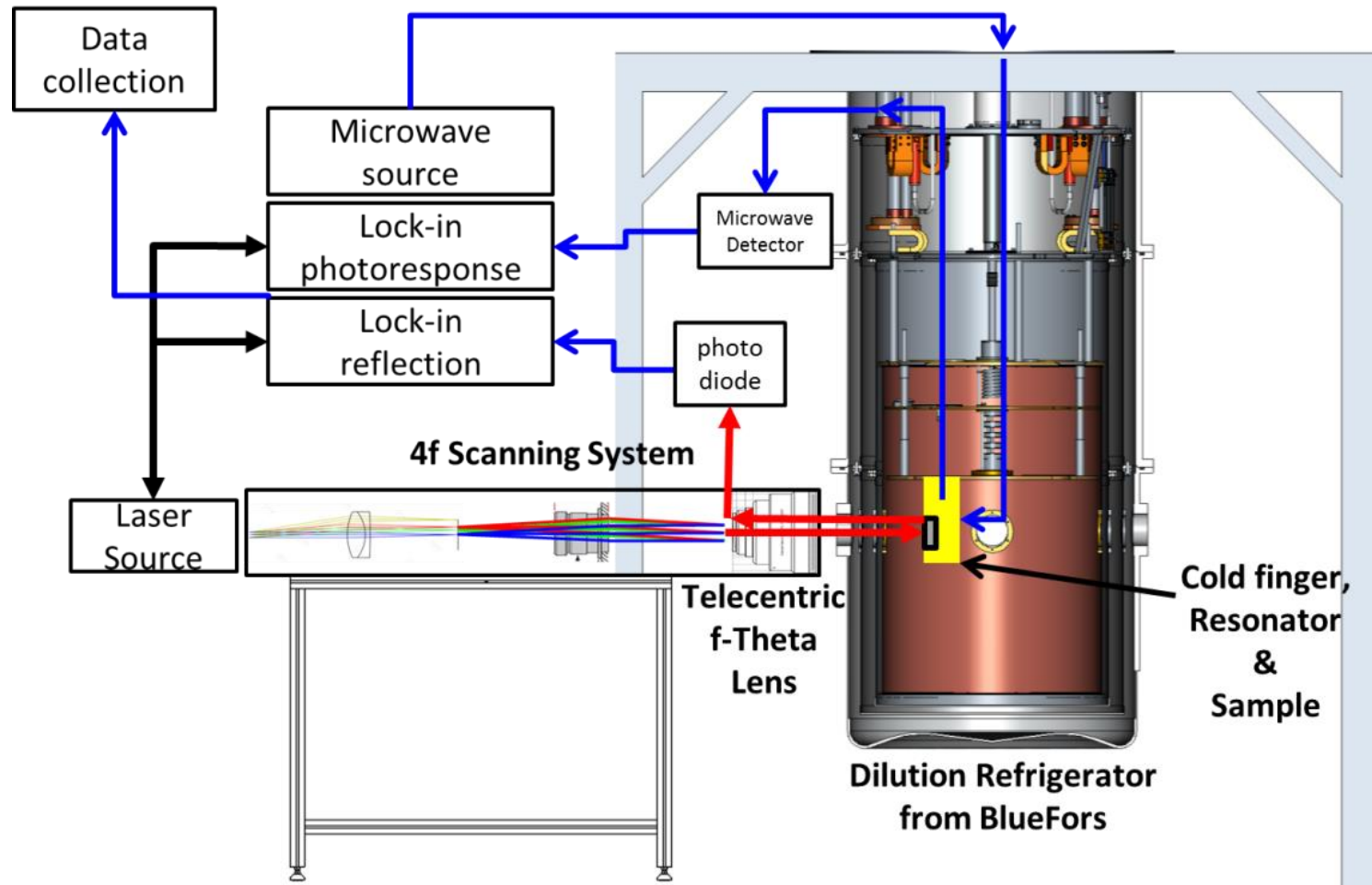
Film thermal diffusivity  $\alpha_{film} = \frac{\kappa}{(\rho C)}$

Substrate thermal diffusivity  $\alpha_{substrate}$

Film / Substrate Thermal Boundary Resistance  $R_{Nb/Cu}$

# Thermal Properties of Nb Coatings and Interfaces

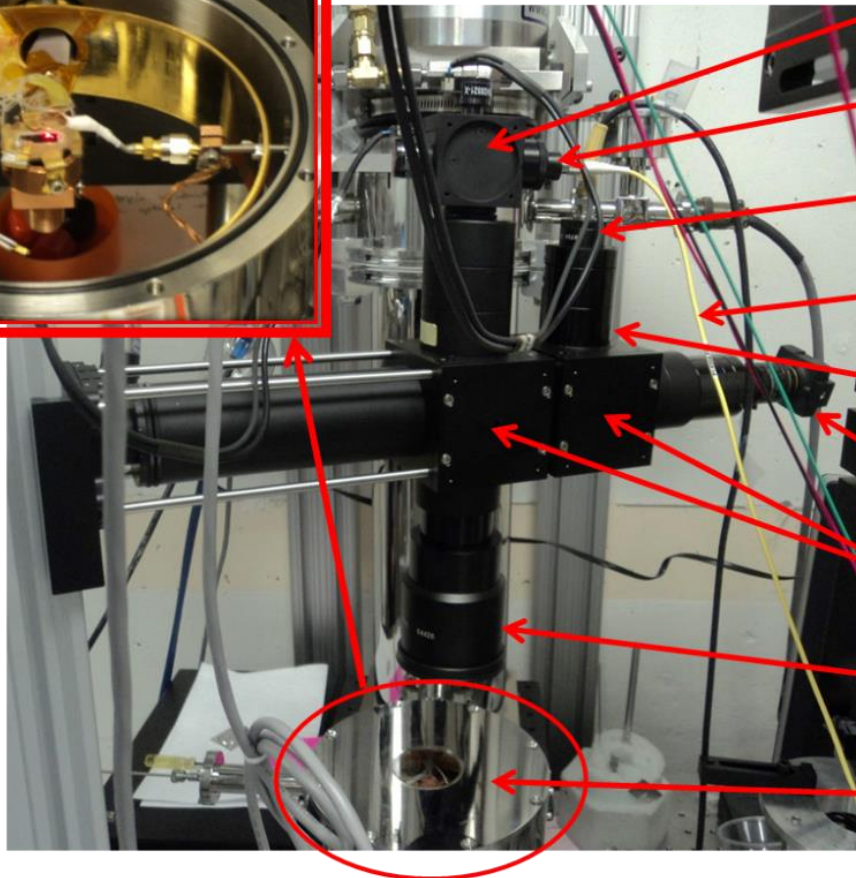
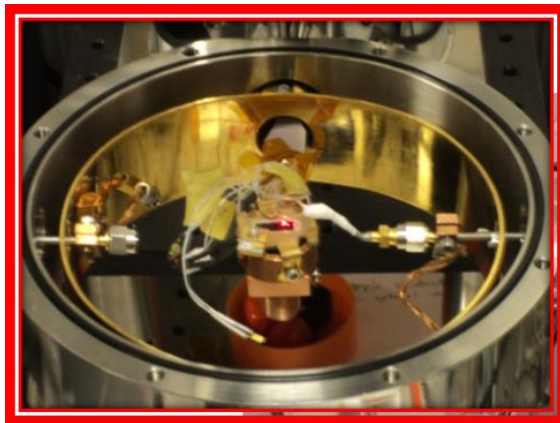
## Laser Scanning Microscope #1 (Dilution Refrigerator)



S. Bae, *et al.*, Rev. Sci. Instrum. 90, 043901 (2019)

# Thermal Properties of Nb Coatings and Interfaces

Laser Scanning Microscope #2 (Gifford-McMahon Refrigerator)



Galvano Mirrors

Collimating lens

Photodiode

Fiber Optic

Focusing Lens

Camera

Beam Splitters

Objective Lens (f=10.0 cm)

Optical Cryostat

# Summary

- A microscopic probe of superconductor nonlinearity is introduced and validated
- 2 classes of Nb nonlinear response are detected and modeled
- Magnetic Microwave Microscopy can be used to extract **local  $T_c$**  and **Effective BCS Gap** at the weak-link and **local RF critical field**

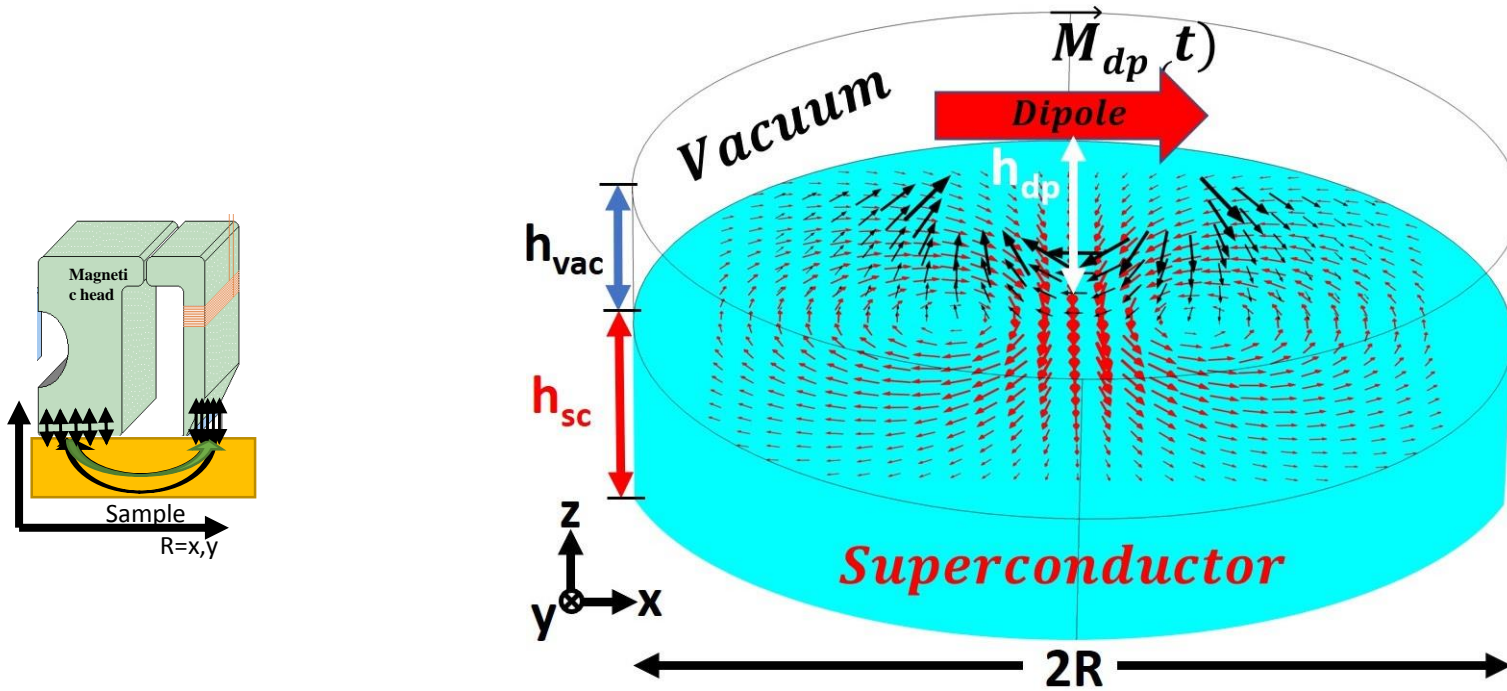
## Future Work

- TDGL Simulations of probe / sample interactions (arXiv:1909.02714)
- Raster Scanning over known defect while imaging onset field
- Measurement of multilayer samples
- Quantitative boundary resistance measurements of coatings
- Residual resistance measurements of SRF cavities to 60 mK

This work is funded by US Department of Energy High Energy Physics program grant # DESC0017931 and the Maryland Quantum Materials Center

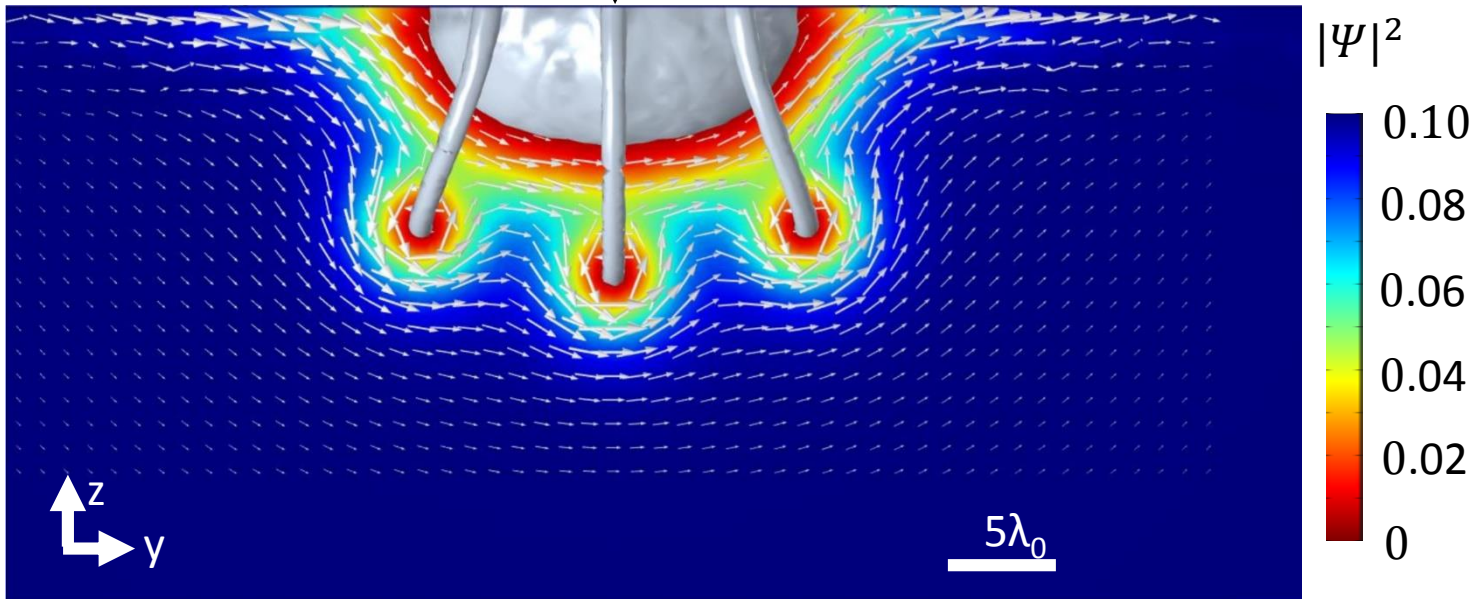
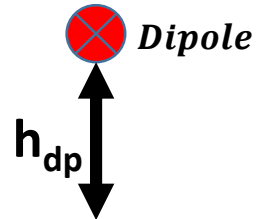
fin

# TDGL simulation setup



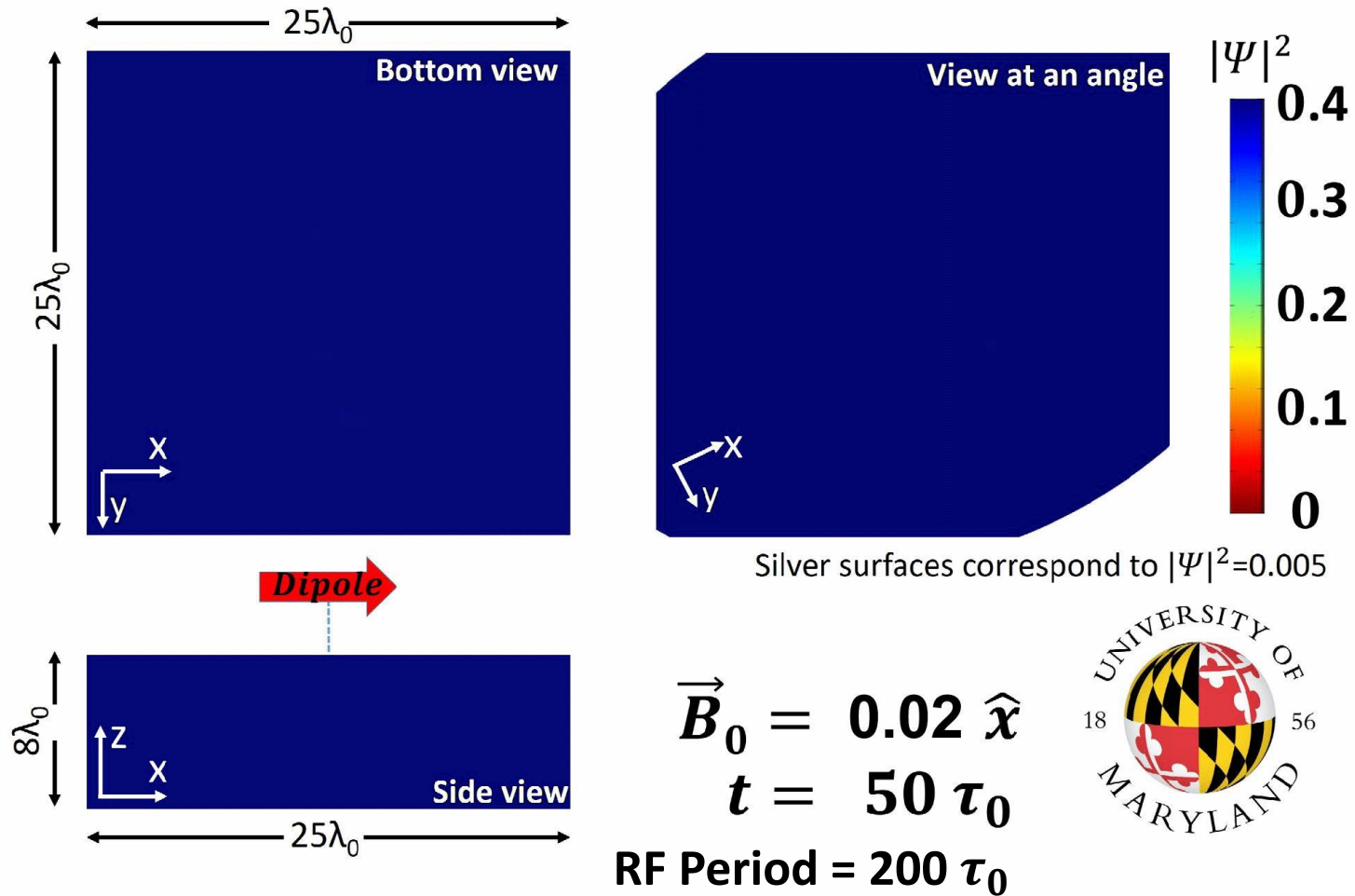
# Screening currents

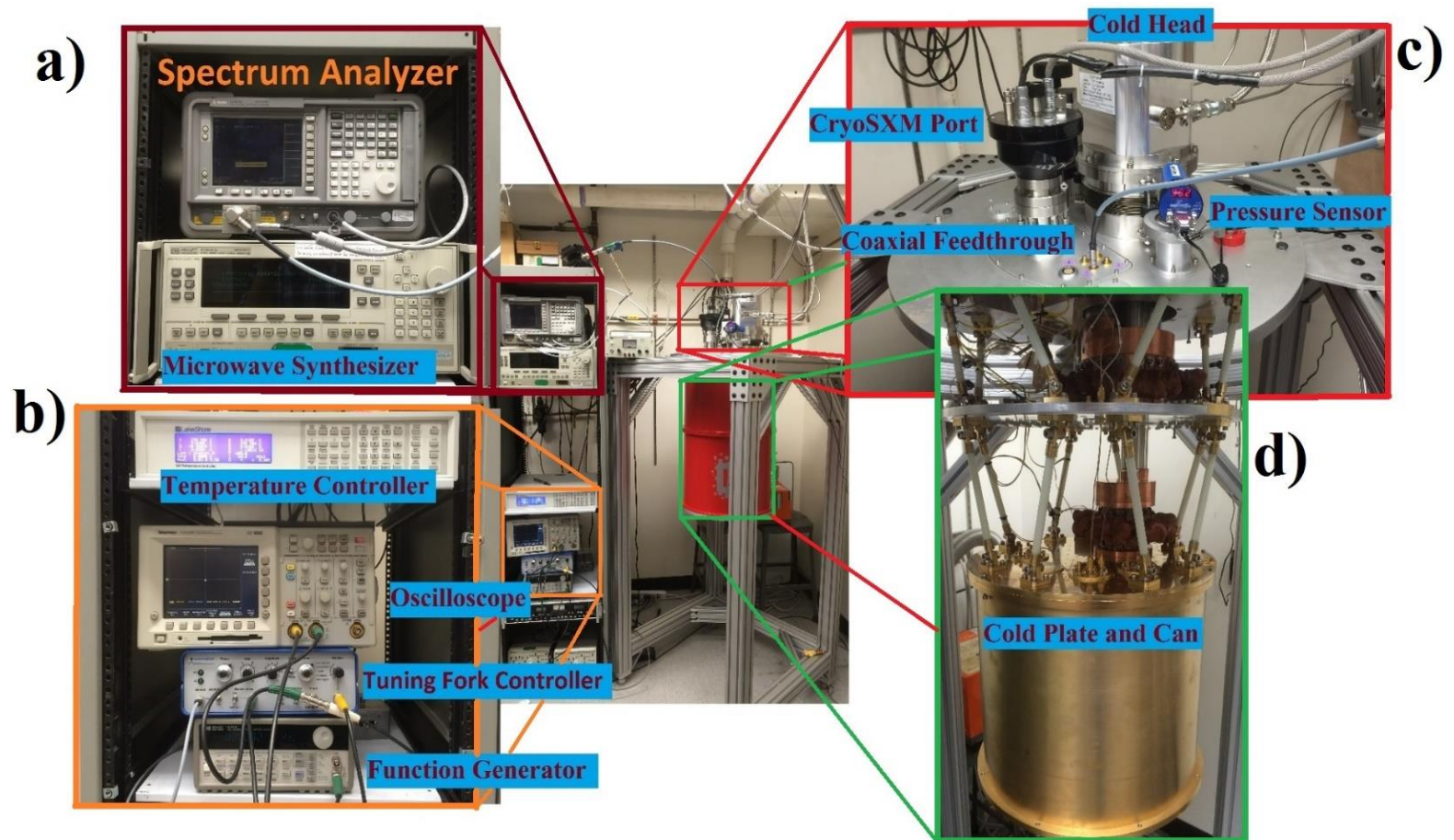
$H_{\text{dipole}} = 12 \lambda$     $\kappa = 1$   
 $B_{\text{dipole}} = 0.3 B_{c2}$     $\eta = 0.2$   
Period =  $200 \tau_0$     $T = 0.9 T_c$   
Frequency  $\approx 5 \text{ GHz}$    NO DEFECTS

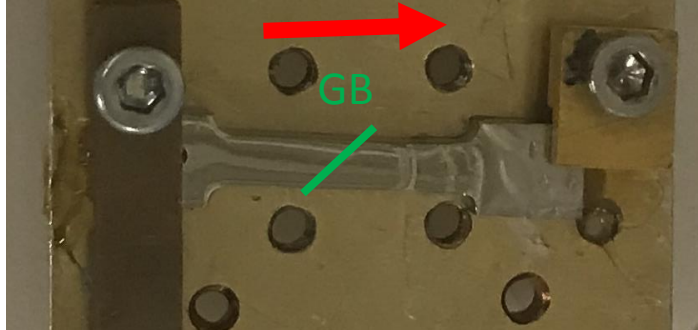




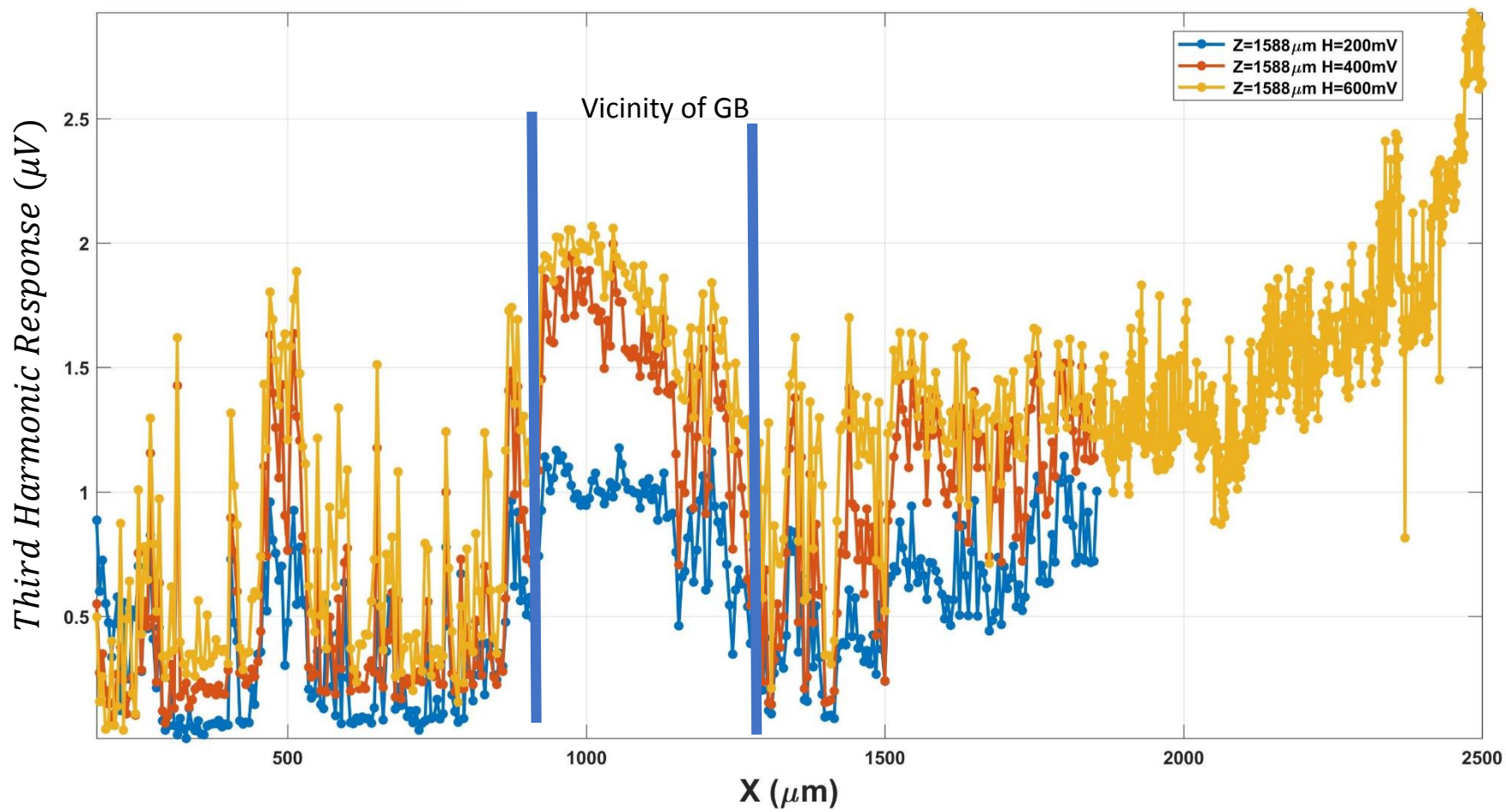
# The evolution of vortex semiloops with rf field amplitude





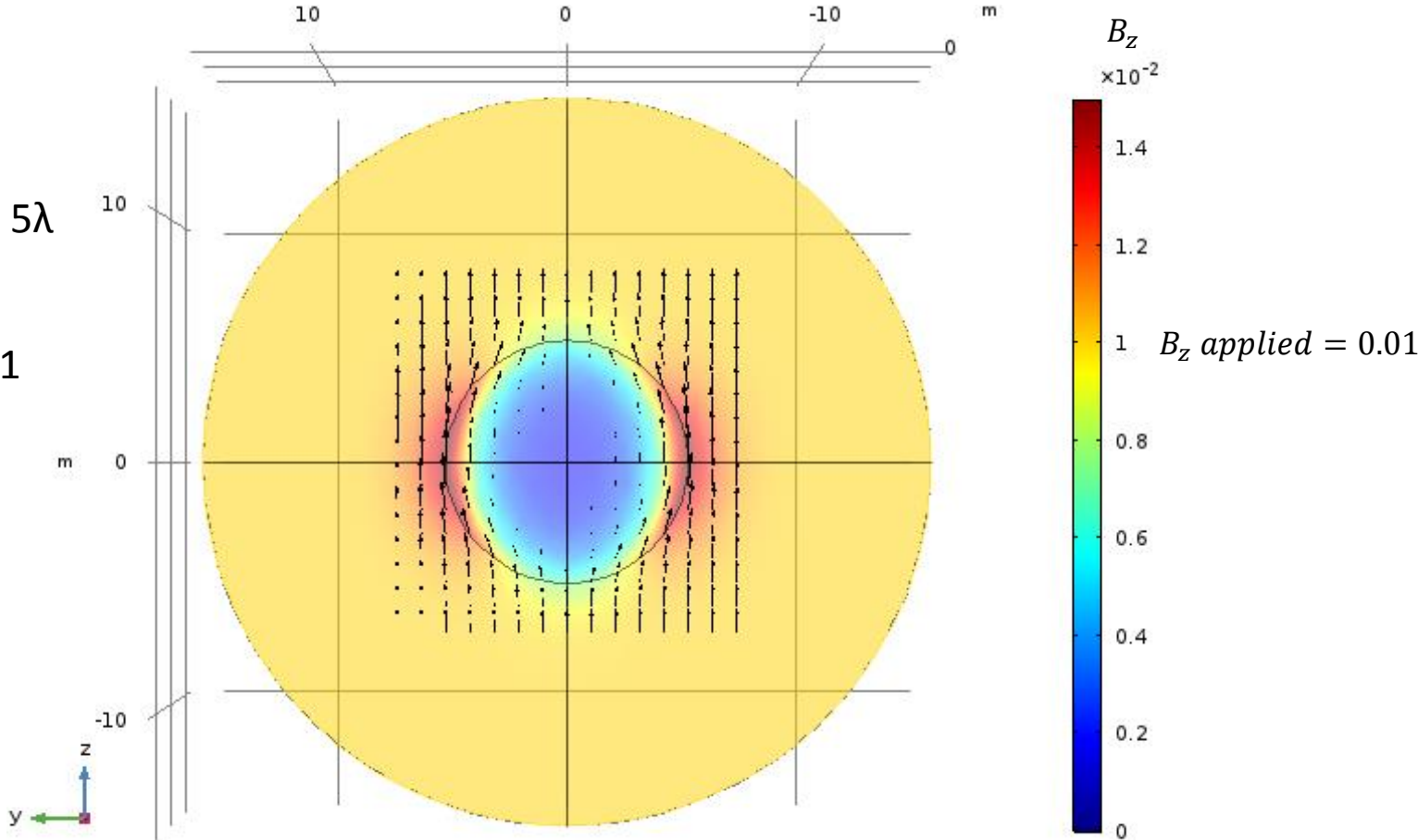


*Bulk Nb from Tom Bieler's Group*



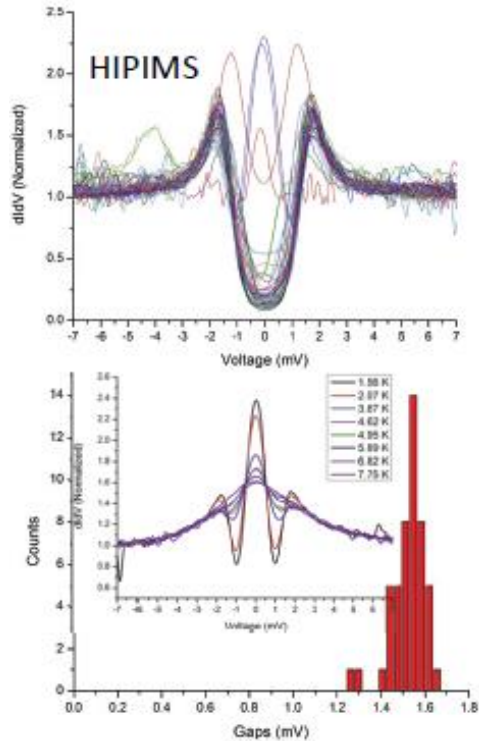
# Superconducting Sphere in a Uniform Static Magnetic Field

Sphere Radius =  $5\lambda$   
 $\kappa = 1, T = 0$ ;  
 $B_z$  applied = 0.01



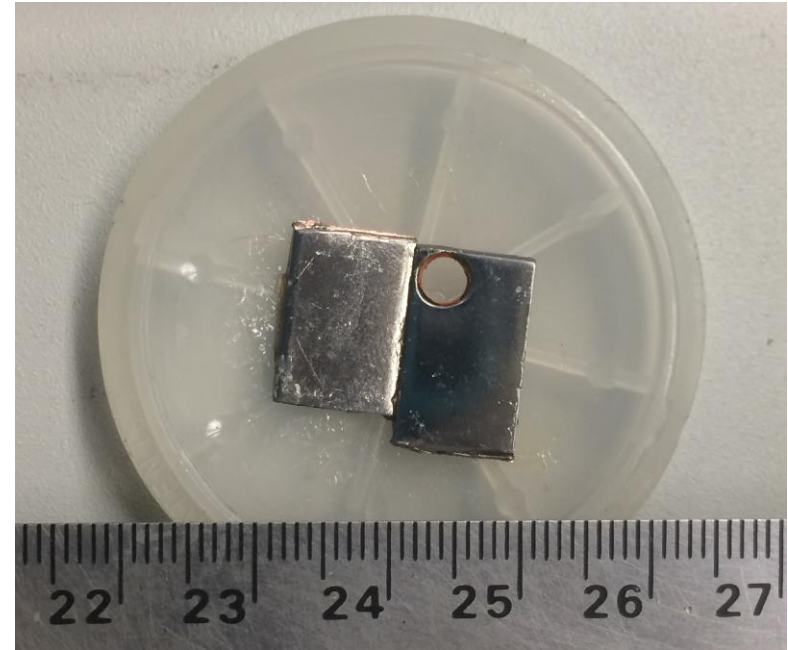
# Nb Film on Copper samples from CERN

- Deposited by high-power impulse magnetron sputtering (HIPIMS)
- Highly Granular (grain size around 10 nm)
- 1  $\mu\text{m}$  Nb / Cu



## Point Contact Spectroscopy:

- ✓ Broadened DOS
- ✓ Finite 0-bias conductance (ZBC)
- ✓ Numerous ZBCP



T. Junginger, SRF2015, TUPB042

# Solution to the RCSJ Model

$$(I_C R_n) \sin \delta + \frac{\Phi_0}{2\pi} \frac{\partial \delta}{\partial t} = (I_\omega R_n) \sin(\omega t)$$

~~$$\frac{\Phi_0 C \partial^2 \delta}{2\pi \partial t^2} + I_C \sin \delta + \frac{\Phi_0}{2\pi R_n} \frac{\partial \delta}{\partial t} = I_\omega \sin(\omega t)$$~~

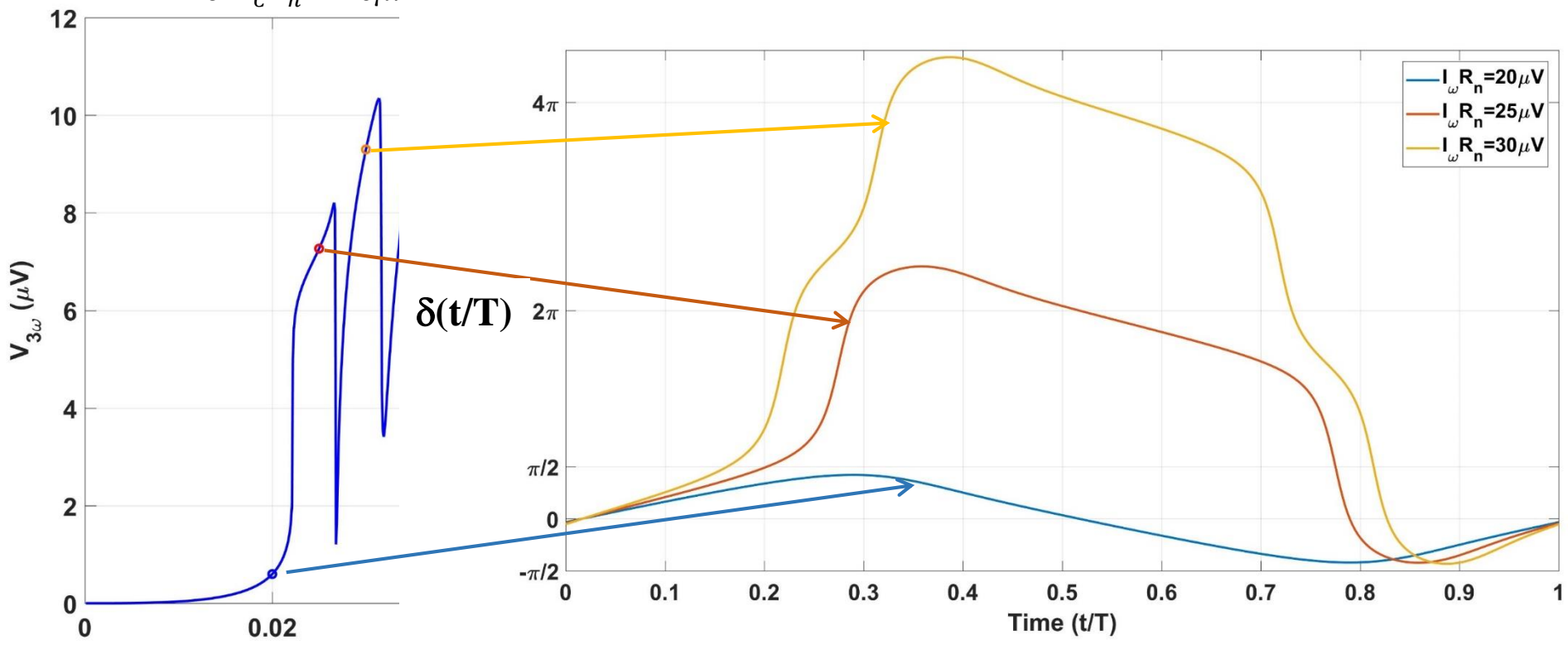
$I_C R_n$  - Fitting Parameter  
 $I_\omega R_n$  - ScalingFactor \* Input RF Field Amplitude (a.u.)

$$\delta(t) \rightarrow V(t) \rightarrow V_{3\omega}$$

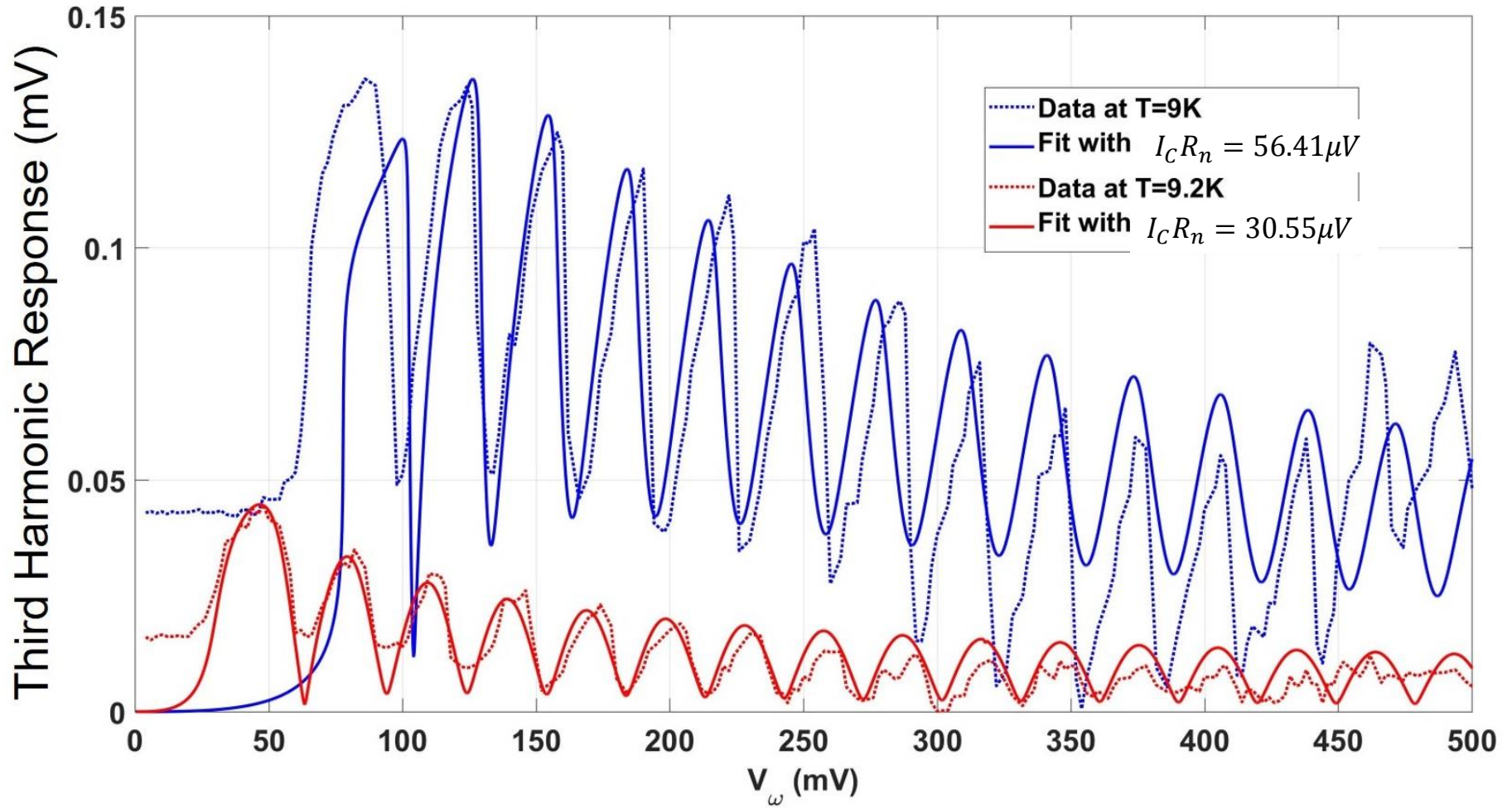
Short Junction Approximation  
 All Dimensions Perpendicular to the field  $\ll \lambda_J$

## Example Solution to the RCSJ Model

For  $I_C R_n = 20 \mu V$



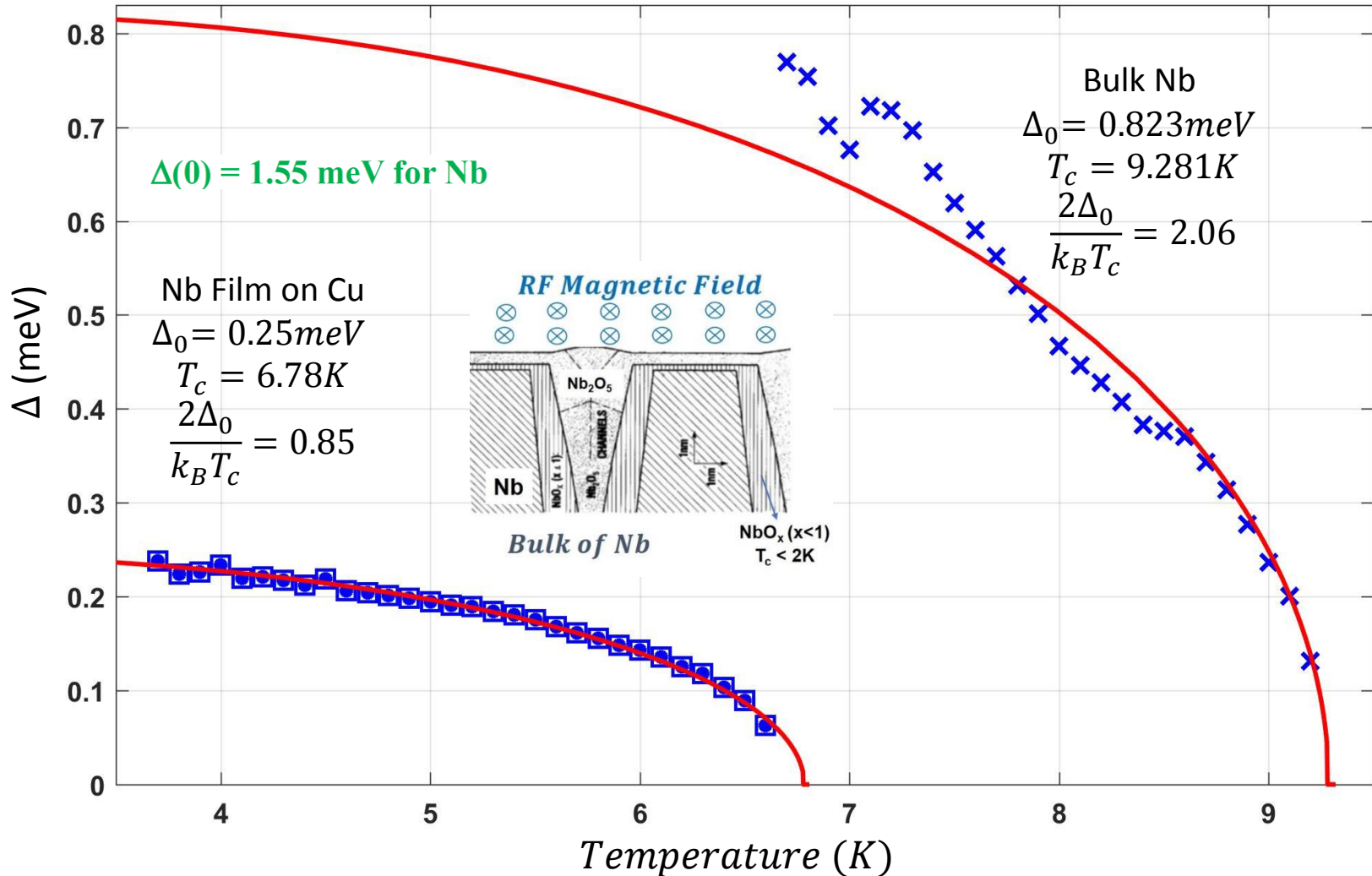
# RCSJ Fit to Bulk Nb Data



# Deduced Energy Gap Temperature Dependence

Assuming AB SIS Tunneling in the JJ

$$I_C R_n = \frac{\pi \Delta}{2e} \tanh\left(\frac{\Delta}{2k_B T}\right) \quad \text{Ambegaokar-Baratoff}$$





# Normalized TDGL Equations

$$\eta \frac{\partial \Psi}{\partial t} = - \left( \frac{i}{\kappa} \vec{\nabla} + \kappa \vec{A} \right)^2 \Psi + (1 - T - |\Psi|^2) \Psi$$

$$\vec{\nabla} \times \vec{\nabla} \times \vec{A} = \underbrace{-\sigma \frac{\partial \vec{A}}{\partial t}}_{J_n} - \underbrace{\frac{i}{2\kappa^2} (\Psi^* \vec{\nabla} \Psi - \Psi \vec{\nabla} \Psi^*) - |\Psi|^2 \vec{A}}_{J_s}$$

$$\kappa = \frac{\lambda(0)}{\xi(0)}; \quad \eta = \frac{\tau_{GL}}{\tau_0}; \quad \vec{B} = \vec{\nabla} \times \vec{A};$$

$$\vec{E} = - \frac{\partial \vec{A}}{\partial t}; \quad T = \text{Temperature};$$

$$|\Psi|^2 = \begin{cases} 1 & \text{Superconducting State} \\ 0 & \text{Normal State} \end{cases}$$

Length measured in units of  $\lambda(0)$

# Further validation with a gap nodal superconductor

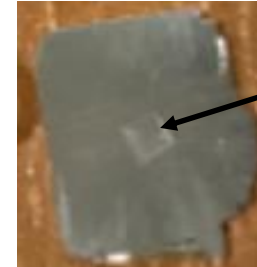


$$T_c \sim 2.4 \text{ K}$$

“Existing evidence of d-wave SC”



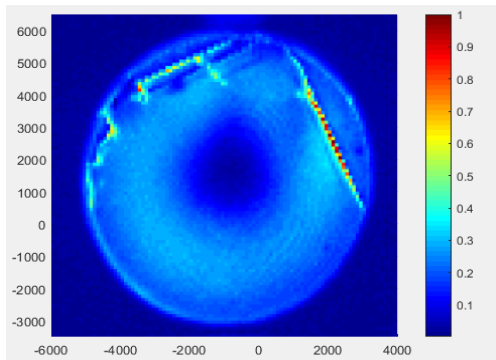
Before polishing



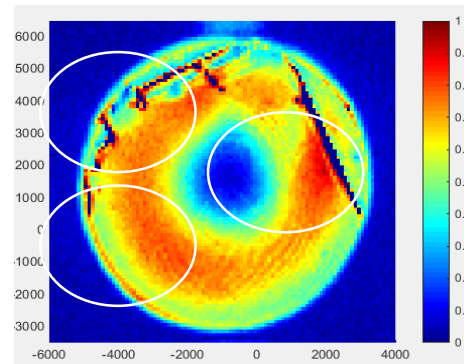
After polishing

Teflon flake

Sample from  
J. Paglione  
6 x 4 mm crystal



PR @ 460 mK



Replot of PR -  
Cut off signal from edge



Sample size < disk

Surface impedance data [ $\delta\lambda(T)$ ,  $R_s(T)$ ] consistent with previously published results

# UTe<sub>2</sub> Photoresponse Images in Rectangular Rutile Dielectric Resonator

